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# PART 2 RF EXPOSURE EVALUATION REPORT

### **Applicant Name:**

Samsung Electronics Co., Ltd. 129, Samsung-ro, Maetan dong, Yeongtong-gu, Suwon-si Gyeonggi-do, 16677, Korea Date of Testing: 3/13/2020 - 04/06/2020 Test Site/Location: PCTEST, Columbia, MD, USA Document Serial No.: 1M2001240012-20-R1.A3L

### FCC ID:

#### A3LSMG986JPN

### APPLICANT:

### SAMSUNG ELECTRONICS CO., LTD.

DUT Type: Application Type: FCC Rule Part(s): Model: Device Serial Numbers: Portable Handset Certification CFR §2.1093 SC-52A, SCG02, SM-G986DS Pre-Production Samples [SN: 0375M, 0834M, 0928M]

Note: This revised Test Report (S/N: 1M2001240012-20-R1.A3L) supersedes and replaces the previously issued test report on the same subject device for the same type of testing as indicated. Please discard or destroy the previously issued test report(s) and dispose of it accordingly.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them. Test results reported herein relate only to the item(s) tested.

**Randy Ortanez** President



FCC ID: A3LSMG986JPN		PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by:
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Document S/N:	Test Dates:	DUT Type:		Page 1 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 1 01 45
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REV 1.0 04/06/2020

# TABLE OF CONTENTS

1	DEVICE UNDER TEST	3
2		4
3	RF EXPOSURE LIMITS	5
4	TIME VARYING TRANSMISSION TEST CASES	6
5	FCC MEASUREMENT PROCEDURES	8
6	MEASUREMENT TEST SETUP	16
7	TEST CONFIGURATIONS	18
8	CONDUCTED TX CASES	21
9	SYSTEM VERIFICATION	35
10	SAR TEST RESULTS FOR SMART TRANSMIT VALIDATION	37
11	EQUIPMENT LIST	41
12	MEASUREMENT UNCERTAINTIES	42
13	CONCLUSION	
14	REFERENCES	44

- APPENDIX A: SAR DIPOLE VERIFICATION PLOTS
- SAR TISSUE SPECIFICATIONS APPENDIX B:
- APPENDIX C: SAR SYSTEM VALIDATION
- APPENDIX D: DUT ANTENNA DIAGRAM & SAR TEST SETUP PHOTOGRAPHS
- APPENDIX E: TEST SEQUENCES
- PROBE AND DIPOLE CALIBRATION CERTIFICATES APPENDIX F:

FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:	'ype:	
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 2 of 45
© 2020 PCTEST	<u>.</u>			REV 1.0

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# **DEVICE UNDER TEST**

#### 1.1 **Device Overview**

Band & Mode	Operating Modes	Tx Frequency
GSM/GPRS/EDGE 850	Voice/Data	824.20 - 848.80 MHz
GSM/GPRS/EDGE 1900	Voice/Data	1850.20 - 1909.80 MHz
UMTS 850	Voice/Data	826.40 - 846.60 MHz
LTE Band 12	Voice/Data	699.7 - 715.3 MHz
LTE Band 13	Voice/Data	779.5 - 784.5 MHz
LTE Band 5 (Cell)	Voice/Data	824.7 - 848.3 MHz
LTE Band 4 (AWS)	Voice/Data	1710.7 - 1754.3 MHz
LTE Band 41	Voice/Data	2498.5 - 2687.5 MHz
2.4 GHz WLAN	Voice/Data	2412 - 2472 MHz
U-NII-1	Voice/Data	5180 - 5240 MHz
U-NII-2A	Voice/Data	5260 - 5320 MHz
U-NII-2C	Voice/Data	5500 - 5720 MHz
U-NII-3	Voice/Data	5745 - 5825 MHz
Bluetooth	Data	2402 - 2480 MHz
NFC	Data	13.56 MHz
ANT+	Data	2402 - 2480 MHz
MST	Data	555 Hz - 8.33 kHz

#### 1.2 Time-Averaging Algorithm for RF Exposure Compliance

The device under test (DUT) contains:

a. Qualcomm<sup>®</sup> SM8250 and SDX55M modems supporting 2G/3G/4G WWAN technologies

Qualcomm<sup>®</sup> SM8250 and SDX55M modems are enabled with Qualcomm<sup>®</sup> Smart Transmit feature. This feature performs time averaging algorithm in real time to control and manage transmitting power and ensure the timeaveraged RF exposure is in compliance with FCC requirements all the time.

The Smart Transmit algorithm maintains the time-averaged transmit power, in turn, time-averaged RF exposure of SAR design target, below the predefined time-averaged power limit (i.e., Plimit for sub-6 radio), for each characterized technology and band.

Smart Transmit allows the device to transmit at higher power instantaneously, as high as *P*<sub>max</sub>, when needed, but enforces power limiting to maintain time-averaged transmit power to Plimit. The Plimit EFS settings and maximum tune up output power Pmax configured for this DUT for various transmit conditions (Device State Index DSI) are shown in Table 7-1. Note that the device uncertainty for sub-6GHz WWAN is 1.0dB for this DUT and the reserve power margin is 3 dB.

This purpose of the Part 2 report is to demonstrate the DUT complies with FCC RF exposure requirement under Tx varying transmission scenarios, thereby validity of Qualcomm<sup>®</sup> Smart Transmit feature implementation in this device. It serves to compliment the Part 0 and Part 1 Test Reports to justify compliance per FCC and ISED.

#### 1.3 Bibliography

Report Type	Report Serial Number
Part 0 Test Report	1M2001240012-19-R1.A3L
Part 1 Test Report	1M2001240012-01-R1.A3L

FCC ID: A3LSMG986JPN	PCTEST		SAMSUNG	Approved by:
	Proud to be part of element			Quality Manager
Document S/N:	Test Dates:	Test Dates: DUT Type:		Page 3 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Fage 5 01 45
© 2020 PCTEST				REV 1.0

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#### 2 INTRODUCTION

The FCC and Innovation, Science, and Economic Development Canada have adopted the guidelines for evaluating the environmental effects of radio frequency (RF) radiation in ET Docket 93-62 on Aug. 6, 1996 and Health Canada Safety Code 6 to protect the public and workers from the potential hazards of RF emissions due to FCC-regulated portable devices. [1]

The safety limits used for the environmental evaluation measurements are based on the criteria published by the American National Standards Institute (ANSI) for localized specific absorption rate (SAR) in IEEE/ANSI C95.1-1992 Standard for Safety Levels with Respect to Human Exposure to Radio Frequency Electromagnetic Fields, 3 kHz to 300 GHz [3] and Health Canada RF Exposure Guidelines Safety Code 6 [22]. The measurement procedure described in IEEE/ANSI C95.3-2002 Recommended Practice for the Measurement of Potentially Hazardous Electromagnetic Fields - RF and Microwave [4] is used for guidance in measuring the Specific Absorption Rate (SAR) due to the RF radiation exposure from the Equipment Under Test (DUT). These criteria for SAR evaluation are similar to those recommended by the International Committee for Non-Ionizing Radiation Protection (ICNIRP) in Biological Effects and Exposure Criteria for Radiofrequency Electromagnetic Fields," Report No. Vol 74. SAR is a measure of the rate of energy absorption due to exposure to an RF transmitting source. SAR values have been related to threshold levels for potential biological hazards.

#### 2.1 **SAR Definition**

Specific Absorption Rate is defined as the time derivative (rate) of the incremental energy (dU) absorbed by (dissipated in) an incremental mass (dm) contained in a volume element (dV) of a given density ( $\rho$ ). It is also defined as the rate of RF energy absorption per unit mass at a point in an absorbing body (see Equation 2-1).

### Equation 2-1 SAR Mathematical Equation

SAR =	d	$\left( \underline{dU} \right)$	d	$\left( \underline{dU} \right)$	
SAN -	$\overline{dt}$	$\left(\frac{dm}{dm}\right)$	$\frac{dt}{dt}$	$\left(\frac{dU}{\rho dv}\right)$	

SAR is expressed in units of Watts per Kilogram (W/kg).

$$SAR = \frac{\sigma \cdot E^2}{\rho}$$

where:

- $\sigma$  = conductivity of the tissue-simulating material (S/m)
- = mass density of the tissue-simulating material  $(kg/m^3)$ ρ
- E = Total RMS electric field strength (V/m)

NOTE: The primary factors that control rate of energy absorption were found to be the wavelength of the incident field in relation to the dimensions and geometry of the irradiated organism, the orientation of the organism in relation to the polarity of field vectors, the presence of reflecting surfaces, and whether conductive contact is made by the organism with a ground plane.[6]

FCC ID: A3LSMG986JPN	Froud to be part of element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 4 of 45
© 2020 PCTEST				REV 1.0

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#### 3 **RF EXPOSURE LIMITS**

#### 3.1 Uncontrolled Environment

UNCONTROLLED ENVIRONMENTS are defined as locations where there is the exposure of individuals who have no knowledge or control of their exposure. The general population/uncontrolled exposure limits are applicable to situations in which the general public may be exposed or in which persons who are exposed as a consequence of their employment may not be made fully aware of the potential for exposure or cannot exercise control over their exposure. Members of the general public would come under this category when exposure is not employment-related; for example, in the case of a wireless transmitter that exposes persons in its vicinity.

#### 3.2 **Controlled Environment**

CONTROLLED ENVIRONMENTS are defined as locations where there is exposure that may be incurred by persons who are aware of the potential for exposure, (i.e. as a result of employment or occupation). In general, occupational/controlled exposure limits are applicable to situations in which persons are exposed as a consequence of their employment, who have been made fully aware of the potential for exposure and can exercise control over their exposure. This exposure category is also applicable when the exposure is of a transient nature due to incidental passage through a location where the exposure levels may be higher than the general population/uncontrolled limits, but the exposed person is fully aware of the potential for exposure and can exercise control over his or her exposure by leaving the area or by some other appropriate means.

Table 3-1 SAR Human Exposure Specified in ANSI/IEEE C95.1-1992 and Health Canada Safety Code 6

HUMAN EXPOSURE LIMITS					
	UNCONTROLLED ENVIRONMENT General Population (W/kg) or (mW/g)	CONTROLLED ENVIRONMENT Occupational (W/kg) or (mW/g)			
Peak Spatial Average SAR Head	1.6	8.0			
Whole Body SAR	0.08	0.4			
<b>Peak Spatial Average SAR</b> Hands, Feet, Ankle, Wrists, etc.	4.0	20			

- The Spatial Peak value of the SAR averaged over any 1 gram of tissue (defined as a tissue volume in the shape of a cube) and over the appropriate 1 averaging time.
- 2. The Spatial Average value of the SAR averaged over the whole body.
- The Spatial Peak value of the SAR averaged over any 10 grams of tissue (defined as a tissue volume in the shape of a cube) and over the appropriate 3. averaging time.

#### 3.3 **Time Averaging Windows for FCC Compliance**

Per October 2018 TCB Workshop Notes, the below time-averaging windows can be used for assessing timeaveraged exposures for devices that are capable of actively monitoring and adjusting power output over time to comply with exposure limits.

Interim Guidance	Frequency (GHz)	Maximum Averaging Time (sec)
SAR	< 3	100
SAN	3 - 6	60
	6 - 10	30
	10 - 16	14
	16 - 24	8
МРЕ	24 - 42	4
	42 - 95	2

FCC ID: A3LSMG986JPN	PCTEST Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 5 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 5 of 45
© 2020 PCTEST				REV 1.0

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### 4 TIME VARYING TRANSMISSION TEST CASES

To validate the time averaging feature and demonstrate the compliance in Tx varying transmission conditions, the following transmission scenarios are covered in the Part 2 test:

- 1. During a time-varying Tx power transmission: To prove that the Smart Transmit feature accounts for Tx power variations in time accurately.
- 2. During a call disconnect and re-establish scenario: To prove that the Smart Transmit feature accounts for history of past Tx power transmissions accurately.
- 3. During a technology/band handover: To prove that the Smart Transmit feature functions correctly during transitions in technology/band.
- 4. During a DSI (Device State Index) change: To prove that the Smart Transmit feature functions correctly during transition from one device state (DSI) to another.
- 5. During an antenna switch: To prove that the Smart Transmit feature functions correctly during transitions in antenna (such as AsDiv scenario) or beams (different antenna array configurations).

As described in Part 0 report, the RF exposure is proportional to the Tx power for a SAR characterized wireless device. Thus, feature validation in Part 2 can be effectively performed through conducted (for f < 6GHz) power measurement. Therefore, the compliance demonstration under dynamic transmission conditions and feature validation are done in conducted power measurement setup for transmission scenario 1 through 5.

To add confidence in the feature validation, the time-averaged SAR measurements are only performed for transmission scenario 1 to avoid the complexity in SAR measurement (such as, for scenario 3 requiring change in SAR probe calibration file to accommodate different bands and/or tissue simulating liquid).

The strategy for testing in Tx varying transmission condition is outlined as follows:

- Demonstrate the total RF exposure averaged over FCC defined time windows does not exceed FCC's SAR limits, through <u>time-averaged power</u> measurements
  - Measure conducted Tx power (for f < 6GHz) versus time
  - Convert it into RF exposure and divide by respective FCC limits to get normalized exposure versus time.
  - Perform running time-averaging over FCC defined time windows.
  - Demonstrate that the total normalized time-averaged RF exposure is less than 1 for all transmission scenarios (i.e., transmission scenarios 1, 2, 3, 4, and 5) at all times.

Mathematical expression:

For < 6 GHz transmission only:

$$1g_or_10gSAR(t) = \frac{conducted_Tx_power(t)}{conducted_Tx_power_P_{limit}} * 1g_or_10gSAR_P_{limit}$$
(1a)

$$\frac{\frac{1}{T_{SAR}}\int_{t-T_{SAR}}^{t} 1g\_or\_10gSAR(t)dt}{FCC SAR limit} \le 1$$
(1b)

where,  $conducted_Tx_power(t)$ ,  $conducted_Tx_power_P_{limit}$ , and  $1g_or_10gSAR_P_{limit}$  correspond to the measured instantaneous conducted Tx power, measured conducted Tx power at  $P_{limit}$ , and measured 1gSAR or 10gSAR values at  $P_{limit}$  corresponding to sub-6 transmission.  $P_{limit}$  values are parameters pre-defined in Part 0 and loaded via Embedded File System (EFS) onto the DUT.  $T_{SAR}$  is the FCC defined time window for sub-6 radio.

	FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
ĺ	Document S/N:	Test Dates:	DUT Type:		Dama Caf 45
	1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 6 of 45
C	2020 PCTEST				DEV 10

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- Demonstrate the total RF exposure averaged over FCC defined time windows does not exceed FCC's • SAR limits, through time-averaged SAR measurements. Note as mentioned earlier, this measurement is performed for transmission scenario 1 only.
  - 0 For sub-6 transmission only, measure instantaneous SAR versus time.
  - Convert it into RF exposure and divide by respective FCC limits to obtain normalized exposure 0 versus time.
  - Perform time averaging over FCC defined time window. 0
  - Demonstrate that the total normalized time-averaged RF exposure is less than 1 for transmission 0 scenario 1 at all times.

Mathematical expression:

\_ For < 6 GHz transmission only:

$$1g\_or\_10gSAR(t) = \frac{pointSAR(t)}{pointSAR\_P_{limit}} * 1g\_or\_10gSAR(t)\_P_{limit}$$
(3a)

$$\frac{\frac{1}{T_{SAR}}\int_{t-T_{SAR}}^{t} 1g\_or\_10gSAR(t)dt}{FCC\ SAR\ limit} \le 1$$
(3b)

where, pointSAR(t),  $pointSAR_P_{limit}$ , and  $1g_or_10gSAR_P_{limit}$  correspond to the measured instantaneous point SAR, measured point SAR at  $P_{limit}$ , and measured 1gSAR or 10gSAR values at  $P_{limit}$  corresponding to sub-6 transmission.

FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates: DUT Type:				
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 7 of 45	
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# 5 FCC MEASUREMENT PROCEDURES

### 5.1 Test sequence determination for validation

Following the FCC recommendation, two test sequences having time-variation in Tx power are predefined for sub-6 (f < 6 GHz) validation:

- Test sequence 1: request DUT's Tx power to be at maximum power, measured  $P_{max}^{\dagger}$ , for 80s, then requesting for half of the maximum power, i.e., measured  $P_{max}/2$ , for the rest of the time.
- Test sequence 2: request DUT's Tx power to vary with time. This sequence is generated relative to measured *P<sub>imit</sub>*, measured *P<sub>limit</sub>* and calculated *P<sub>reserve</sub>* (= measured *P<sub>limit</sub>* in dBm *Reserve\_power\_margin* in dB) of DUT based on measured *P<sub>limit</sub>*.

The details for generating these two test sequences is described and listed in Appendix E.

**NOTE:** For test sequence generation, "measured  $P_{limit}$ " and "measured  $P_{max}$ " are used instead of the " $P_{limit}$ " specified in EFS entry and " $P_{max}$ " specified for the device, because the Smart Transmit feature operates against the actual power level of the " $P_{limit}$ " that was calibrated for the DUT. The "measured  $P_{limit}$ " accurately reflects what the feature is referencing to, therefore, it should be used during feature validation testing. The RF tune up and device-to-device variation are already considered in Part 0 report prior to determining  $P_{limit}$ .

### 5.2 Test configuration selection criteria for validating Smart Transmit feature

For validating the Smart Transmit feature, this section provides the general guidance to select test cases.

# 5.2.1 Test configuration selection for time-varying Tx power transmission

The Smart Transmit time averaging feature operation is independent of bands, modes, and channels for a given technology. Hence, validation of Smart Transmit in one band/mode/channel per technology is sufficient. Two bands per technology are proposed and selected for this testing to provide high confidence in this validation.

The criteria for the selection are based on the  $P_{limit}$  values determined in Part 0 report. Select two bands<sup>\*</sup> in each supported technology that correspond to least<sup>\*\*</sup> and highest<sup>\*\*\*</sup>  $P_{limit}$  values that are less than  $P_{max}$  for validating Smart Transmit.

\* If one  $P_{limit}$  level applies to all the bands within a technology, then only one band needs to be tested. In this case, within the bands having the same  $P_{limit}$ , the radio configuration (e.g., # of RBs, channel#) and device position that correspond to the highest *measured* 1gSAR at  $P_{limit}$  shown in Part 1 report is selected.

\*\* In case of multiple bands having the same least  $P_{limit}$  within the technology, then select the band having the highest *measured* 1gSAR at  $P_{limit}$ .

FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element			Approved by: Quality Manager	
Document S/N:	Test Dates:	Test Dates: DUT Type:			
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 8 of 45	
© 2020 DOTEST				DEV/1	

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REV 1.0 04/06/2020 \*\*\* The band having a higher  $P_{limit}$  needs to be properly selected so that the power limiting enforced by Smart Transmit can be validated using the pre-defined test sequences. If the highest  $P_{limit}$  in a technology is too high where the power limiting enforcement is not needed when testing with the predefined test sequences, then the next highest level is checked. This process is continued within the technology until the second band for validation testing is determined.

### 5.2.2 Test configuration selection for change in call

The criteria to select a test configuration for call-drop measurement is:

- Select technology/band with least *P*<sub>limit</sub> among all supported technologies/bands, and select the radio configuration (e.g., # of RBs, channel#) in this technology/band that corresponds to the highest *measured* 1gSAR at *P*<sub>limit</sub> listed in Part 1 report.
- In case of multiple bands having same least *P*<sub>limit</sub>, then select the band having the highest *measured* 1gSAR at *P*<sub>limit</sub> in Part 1 report.

This test is performed with the DUT's Tx power requested to be at maximum power, the above band selection will result in Tx power enforcement (i.e., DUT forced to have Tx power at  $P_{reserve}$ ) for longest duration in one FCC defined time window. The call change (call drop/reestablish) is performed during the Tx power enforcement duration (i.e., during the time when DUT is forced to have Tx power at  $P_{reserve}$ ). One test is sufficient as the feature operation is independent of technology and band.

### 5.2.3 **Test configuration selection for change in technology/band**

The selection criteria for this measurement is, for a given antenna, to have DUT switch from a technology/band with lowest  $P_{limit}$  within the technology group (in case of multiple bands having the same  $P_{limit}$ , then select the band with highest *measured* 1gSAR at  $P_{limit}$ ) to a technology/band with highest  $P_{limit}$  within the technology group, in case of multiple bands having the same  $P_{limit}$ , then select the band with highest  $P_{limit}$  in Part 1 report, or vice versa.

This test is performed with the DUT's Tx power requested to be at maximum power, the technology/band switch is performed during Tx power enforcement duration (i.e., during the time when DUT is forced to have Tx power at  $P_{reserve}$ ).

### 5.2.4 **Test configuration selection for change in antenna**

The criteria to select a test configuration for antenna switch measurement is:

- Whenever possible and supported by the DUT, first select antenna switch configuration within the same technology/band (i.e., same technology and band combination).
- Then, select any technology/band that supports multiple Tx antennas, and has the highest difference in *P*<sub>limit</sub> among all supported antennas.
- In case of multiple bands having same difference in *P*<sub>limit</sub> among supported antennas, then select the band having the highest *measured* 1gSAR at *P*<sub>limit</sub> in Part 1 report.

This test is performed with the DUT's Tx power requested to be at maximum power in selected technology/band, and antenna change is conducted during Tx power enforcement duration (i.e., during the time when DUT is forced to have Tx power at  $P_{reserve}$ ).

### 5.2.5 Test configuration selection for change in DSI

The criteria to select a test configuration for DSI change test is

	FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:		Daga 0 of 45
	1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 9 of 45
6	2020 DOTEOT				

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REV 1.0 04/06/2020

Select a technology/band having the  $P_{limit} < P_{max}$  within any technology and DSI group, and • for the same technology/band having a different Plimit in any other DSI group. Note that the selected DSI transition need to be supported by the device.

This test is performed with the DUT's Tx power requested to be at maximum power in selected technology/band, and DSI change is conducted during Tx power enforcement duration (i.e., during the time when DUT is forced to have Tx power at *P*<sub>reserve</sub>).

### 5.3 Test procedures for conducted power measurements

This section provides general conducted power measurement procedures to perform compliance test under dynamic transmission scenarios described in Section 4. In practice, an adjustment can be made in these procedures. The justification/clarification may be provided.

#### Time-varying Tx power transmission scenario 5.3.1

This test is performed with the two pre-defined test sequences described in Section 5.1 for all the technologies and bands selected in Section 5.2.1. The purpose of the test is to demonstrate the effectiveness of power limiting enforcement and that the time-averaged SAR (corresponding timeaveraged Tx power) does not exceed the FCC limit at all times (see Eq. (1a) and (1b)).

### **Test procedure**

- 1. Measure  $P_{max}$ , measure  $P_{limit}$  and calculate  $P_{reserve}$  (= measured  $P_{limit}$  in dBm Reserve power margin in dB) and follow Section 5.1 to generate the test sequences for all the technologies and bands selected in Section 5.2.1. Both test sequence 1 and test sequence 2 are created based on measured P<sub>max</sub> and measured P<sub>limit</sub> of the DUT. Test condition to measure  $P_{max}$  and  $P_{limit}$  is:
  - a. Measure *P<sub>max</sub>* with Smart Transmit disabled and callbox set to request maximum power.
  - b. Measure *P<sub>limit</sub>* with Smart Transmit enabled and *Reserve\_power\_margin* set to 0 dB, callbox set to request maximum power.
- 2. Set Reserve power margin to actual (intended) value (3dB for this DUT based on Part 1 report) and reset power on DUT to enable Smart Transmit, establish radio link in desired radio configuration, with callbox requesting the DUT's Tx power to be at pre-defined test sequence 1, measure and record Tx power versus time, and then convert the conducted Tx power into 1gSAR or 10gSAR value (see Eq. (1a)) using measured Plimit from above Step 1. Perform running time average to determine time-averaged power and 1gSAR or 10gSAR versus time as illustrated in Figure 5-1 where using 100-seconds time window as an example.

Note: In Eq.(1a), instantaneous Tx power is converted into instantaneous 1gSAR or 10gSAR value by applying the measured worst-case 1gSAR or 10gSAR value at Plimit for the corresponding technology/band/antenna/DSI reported in Part 1 report.

Note: For an easier computation of the running time average, 0 dBm can be added at the beginning of the test sequences the length of the responding time window, for example, add 0dBm for 100-seconds so the running time average can be directly performed starting with the first 100-seconds data using excel spreadsheet. This technique applies to all tests performed in this Part 2 report for easier time-averaged computation using excel spreadsheet.

FCC ID: A3LSMG986JPN	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	ocument S/N: Test Dates: DUT Type:				
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 10 of 45	
© 2020 PCTEST				REV 1.0	

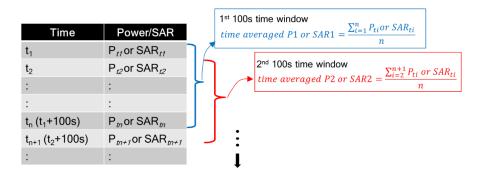


Figure 5-1 **Running Average Illustration** 

- 3. Make one plot containing:
  - a. Instantaneous Tx power versus time measured in Step 2,
  - b. Requested Tx power used in Step 2 (test sequence 1),
  - c. Computed time-averaged power versus time determined in Step 2,
  - d. Time-averaged power limit (corresponding to FCC SAR limit of 1.6 W/kg for 1gSAR or 4.0W/kg for 10gSAR) given by

Time avearged power limit = meas.  $P_{limit} + 10 \times \log(\frac{FCC SAR limit}{meas SAR Plimit})$ (5a)

where meas. P<sub>limit</sub> and meas. SAR\_Plimit correspond to measured power at P<sub>limit</sub> and measured SAR at Plimit.

- 4. Make another plot containing:
  - a. Computed time-averaged 1gSAR or 10gSAR versus time determined in Step 2
  - b. FCC 1qSAR<sub>limit</sub> of 1.6W/kg or FCC 10qSAR<sub>limit</sub> of 4.0W/kg.
- 5. Repeat Steps 2 ~ 4 for pre-defined test sequence 2 and replace the requested Tx power (test sequence 1) in Step 2 with test sequence 2.
- 6. Repeat Steps 2 ~ 5 for all the selected technologies and bands.
- 7. The validation criteria are, at all times, the time-averaged power versus time shown in Step 3 plot shall not exceed the time-averaged power limit (defined in Eq. (5a)), in turn, the timeaveraged 1gSAR or 10gSAR versus time shown in Step 4 plot shall not exceed the FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR (i.e., Eq. (1b)).

#### 5.3.2 Change in call scenario

This test is to demonstrate that Smart Transmit feature accurately accounts for the past Tx powers during time-averaging when a new call is established.

The call disconnect and re-establishment needs to be performed during power limit enforcement, i.e., when the DUT's Tx power is at Preserve level, to demonstrate the continuity of RF exposure management and limiting in call change scenario. In other words, the RF exposure averaged over any FCC defined time window (including the time windows containing the call change) doesn't exceed FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.

	FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:		Dage 11 of 15
	1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 11 of 45
0	2020 PCTEST				REV 1.

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### Test procedure

- 1. Measure Plimit for the technology/band selected in Section 5.2.2. Measure Plimit with Smart Transmit enabled and *Reserve power margin* set to 0 dB, callbox set to request maximum power.
- 2. Set Reserve power margin to actual (intended) value and reset power on DUT to enable Smart Transmit.
- 3. Establish radio link with callbox in the selected technology/band.
- 4. Request DUT's Tx power at 0 dBm for at least one time window specified for the selected technology/band, followed by requesting DUT's Tx power to be at maximum power for about ~60 seconds, and then drop the call for ~10 seconds. Afterwards, re-establish another call in the same radio configuration (i.e., same technology/band/channel) and continue callbox requesting DUT's Tx power to be at maximum power for the remaining time of at least another full duration of the specified time window. Measure and record Tx power versus time. Once the measurement is done, extract instantaneous Tx power versus time, convert the measured conducted Tx power into 1gSAR or 10gSAR value using Eq. (1a), and then perform the running time average to determine time-averaged power and 1gSAR or 10gSAR versus time.
  - NOTE: In Eq.(1a), instantaneous Tx power is converted into instantaneous 1gSAR or 10gSAR value by applying the measured worst-case 1gSAR or 10gSAR value at Plimit for the corresponding technology/band/antenna/DSI reported in Part 1 report.
- 5. Make one plot containing: (a) instantaneous Tx power versus time, (b) requested power, (c) computed time-averaged power, (d) time-averaged power limit calculated using Eq.(5a).
- 6. Make another plot containing: (a) computed time-averaged 1gSAR or 10gSAR versus time, and (b) FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.

The validation criteria are, at all times, the time-averaged power versus time shall not exceed the time-averaged power limit (defined in Eq.(5a)), in turn, the time-averaged 1gSAR or 10gSAR versus time shall not exceed the FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR (i.e., Eq. (1b)).

### 5.3.3 Change in technology and band

This test is to demonstrate the correct power control by Smart Transmit during technology switches and/or band handovers.

Similar to the change in call test in Section 5.3.2, to validate the continuity of RF exposure limiting during the transition, the technology and band handover needs to be performed when DUT's Tx power is at Preserve level (i.e., during Tx power enforcement) to make sure that the DUT's Tx power from previous Preserve level to the new Preserve level (corresponding to new technology/band). Since the P<sub>limit</sub> could vary with technology and band, Eq. (1a) can be written as follows to convert the instantaneous Tx power in 1gSAR or 10gSAR exposure for the two given radios, respectively:

$$1g_or_10gSAR_1(t) = \frac{conducted_Tx_power_1(t)}{conducted_Tx_power_P_{limit_1}} * 1g_or_10gSAR_P_{limit_1}$$
(6a)

FCC ID: A3LSMG986JPN	PCTEST <sup>®</sup> Proud to be part of <sup>®</sup> element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 12 of 15
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 12 of 45
© 2020 PCTEST				REV 1.0

2020 PCTEST

$$1g_or_10gSAR_2(t) = \frac{conducted_Tx_power_2(t)}{conducted_Tx_power_P_{limit_2}} * 1g_or_10gSAR_P_{limit_2}$$
(6b)

$$\frac{1}{T_{SAR}} \left[ \int_{t-T_{SAR}}^{t_1} \frac{1g\_or\_10gSAR_1(t)}{FCC\ SAR\ limit} dt + \int_{t-T_{SAR}}^{t} \frac{1g\_or\_10gSAR_2(t)}{FCC\ SAR\ limit} dt \right] \le 1$$
(6c)

where, conducted\_Tx\_power\_1(t), conducted\_Tx\_power\_P<sub>limit</sub>, and 1g\_or\_10gSAR\_P<sub>limit</sub> correspond to the measured instantaneous conducted Tx power, measured conducted Tx power at *P*<sub>limit</sub>, and measured 1gSAR or 10gSAR value at *P*<sub>limit</sub> of technology1/band1; conducted Tx power 2(t), conducted Tx power  $P_{limit 2}(t)$ , and 1g or 10gSAR  $P_{limit 2}$ correspond to the measured instantaneous conducted Tx power, measured conducted Tx power at *P*<sub>limit</sub>, and measured 1gSAR or 10gSAR value at *P*<sub>limit</sub> of technology2/band2. Transition from technology1/band1 to the technology2/band2 happens at time-instant ' $t_1$ '.

### Test procedure

- 1. Measure *P*<sub>limit</sub> for both the technologies and bands selected in Section 5.2.3. Measure *P*<sub>limit</sub> with Smart Transmit enabled and Reserve\_power\_margin set to 0 dB, callbox set to request maximum power.
- 2. Set Reserve power margin to actual (intended) value and reset power on DUT to enable Smart Transmit
- 3. Establish radio link with callbox in first technology/band selected.
- Request DUT's Tx power at 0 dBm for at least one time window specified for the selected technology/band, followed by requesting DUT's Tx power to be at maximum power for about ~60 seconds, and then switch to second technology/band selected. Continue with callbox requesting DUT's Tx power to be at maximum power for the remaining time of at least another full duration of the specified time window. Measure and record Tx power versus time for the full duration of the test.
- Once the measurement is done, extract instantaneous Tx power versus time, and convert the conducted Tx power into 1gSAR or 10gSAR value using Eq. (6a) and (6b) and corresponding measured P<sub>limit</sub> values from Step 1 of this section. Perform the running time average to determine time-averaged power and 1gSAR or 10gSAR versus time.

NOTE: In Eq.(6a) & (6b), instantaneous Tx power is converted into instantaneous 1gSAR or 10gSAR value by applying the measured worst-case 1gSAR or 10gSAR value at Plimit for the corresponding technology/band/antenna/DSI reported in Part 1 report.

- 6. Make one plot containing: (a) instantaneous Tx power versus time, (b) requested power, (c) computed time-averaged power, (d) time-averaged power limit calculated using Eq.(5a).
- 7. Make another plot containing: (a) computed time-averaged 1gSAR or 10gSAR versus time, and (b) FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.

The validation criteria are, at all times, the time-averaged 1gSAR or 10gSAR versus time shall not exceed the FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR (i.e., Eq. (6c)).

#### 5.3.4 Change in antenna

This test is to demonstrate the correct power control by Smart Transmit during antenna switches from one antenna to another. The test procedure is identical to Section 5.3.3, by replacing

FCC ID: A3LSMG986JPN	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 12 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 13 of 45
© 2020 PCTEST				REV 1.0

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technology/band switch operation with antenna switch. The validation criteria are, at all times. the time-averaged 1gSAR or 10gSAR versus time shall not exceed FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.

NOTE: If the DUT does not support antenna switch within the same technology/band, but has multiple antennas to support different frequency bands, then the antenna switch test is included as part of change in technology and band (Section 5.3.3) test.

#### 5.3.5Change in DSI

This test is to demonstrate the correct power control by Smart Transmit during DSI switches from one DSI to another. The test procedure is identical to Section 5.3.3, by replacing technology/band switch operation with DSI switch. The validation criteria are, at all times, the time-averaged 1gSAR or 10gSAR versus time shall not exceed FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.

### 5.4 Test procedure for time-varying SAR measurements

This section provides general time-varying SAR measurement procedures to perform compliance test under dynamic transmission scenarios described in Section 4. In practice, an adjustment can be made in these procedures. The justification/clarification may be provided.

To perform the validation through SAR measurement for transmission scenario 1 described in Section 4, the "path loss" between callbox antenna and DUT needs to be calibrated to ensure that the DUT Tx power reacts to the requested power from callbox in a radiated call. It should be noted that when signaling in closed loop mode, protocol-level power control is in play, resulting in DUT not solely following callbox TPC (Tx power control) commands. In other words, DUT response has many dependencies (RSSI, guality of signal, path loss variation, fading, etc.,) other than just TPC commands. These dependencies have less impact in conducted setup (as it is a controlled environment and the path loss can be very well calibrated) but have significant impact on radiated testing in an uncontrolled environment, such as SAR test setup. Therefore, the deviation in DUT Tx power from callbox requested power is expected, however the timeaveraged SAR should not exceed FCC SAR requirement at all times as Smart Transmit controls Tx power at DUT.

The following steps are for time averaging feature validation through SAR measurement:

- 1. "Path Loss" calibration: Place the DUT against the phantom in the worst-case position determined based on Section 5.2.1. For each band selected, prior to SAR measurement, perform "path loss" calibration between callbox antenna and DUT. Since the SAR test environment is not controlled and well calibrated for OTA (Over the Air) test, extreme care needs to be taken to avoid the influence from reflections. The test setup is described in Section 6.2.
- 2. Time averaging feature validation:
  - For a given radio configuration (technology/band) selected in Section 5.2.1, enable Smart Transmit and set *Reserve\_power\_margin* to 0 dB, with callbox to request maximum power, perform area scan, conduct pointSAR measurement at peak location of the area scan. This point SAR value, *pointSAR\_P<sub>limit</sub>*, corresponds to point SAR at the measured *P*<sub>limit</sub> (i.e., measured *P*<sub>limit</sub> from the DUT in Step 1 of Section 5.3.1).

	FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:		Dage 14 of 45
	1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 14 of 45
0	2020 PCTEST				REV 1.

<sup>© 2020</sup> PCTEST

Set Reserve power margin to actual (intended) value and reset power on DUT to ii enable Smart Transmit. Note, if Reserve\_power\_margin cannot be set wirelessly, care must be taken to re-position the DUT in the exact same position relative to the SAM phantom as in above Step 2.i. Establish radio link in desired radio configuration, with callbox requesting the DUT's Tx power at power levels described by test sequence 1 generated in Step 1 of Section 5.3.1, conduct point SAR measurement versus time at peak location of the area scan determined in Step 2.i of this section. Once the measurement is done, extract instantaneous point SAR vs time data, pointSAR(t), and convert it into instantaneous 1gSAR or 10gSAR vs. time using Eq. (3a), re-written below:

 $1g_or_10gSAR(t) = \frac{pointSAR(t)}{pointSAR_{P_{limit}}} * 1g_or_10gSAR_{P_{limit}}$ 

where, pointSAR\_P<sub>limit</sub> is the value determined in Step 2.i, and pointSAR(t) is the instantaneous point SAR measured in Step 2.ii, 1g\_or\_10gSAR\_P<sub>limit</sub> is the measured 1gSAR or 10gSAR value listed in Part 1 report.

- iii Perform 100s running average to determine time-averaged 1gSAR or 10gSAR versus time.
- Make one plot containing: (a) time-averaged 1gSAR or 10gSAR versus time determined iv in Step 2.iii of this section, (b) FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.
- Repeat 2.ii ~ 2.iv for test sequence 2 generated in Step 1 of Section 5.3.1. v
- vi Repeat 2.i ~ 2.v for all the technologies and bands selected in Section 5.2.1.

The time-averaging validation criteria for SAR measurement is that, at all times, the timeaveraged 1gSAR or 10gSAR versus time shall not exceed FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR (i.e., Eq. (3b)).

FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:				
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 15 of 45	
© 2020 PCTEST				REV 1.0	

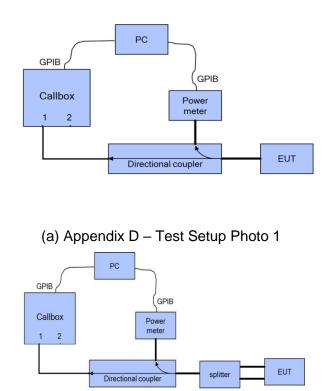
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#### 6 **MEASUREMENT TEST SETUP**

#### 6.1 **Conducted Measurement Test setup**

The Rohde & Schwarz CMW500 callbox is used in this test. The test setup schematic is shown in Figure 6-1a (Appendix D – Test Setup Photo 1) for measurements with a single antenna of DUT, and in Figure 6-1b (Appendix D – Test Setup Photo 2) for measurements involving antenna switch. For single antenna measurement, one port (RF1 COM) of the callbox is connected to the RF port of the DUT using a directional coupler. For antenna switch measurement, one port (RF1 COM) of the callbox used for signaling two different technologies is connected to a combiner, which is in turn connected to a directional coupler. The other end of the directional coupler is connected to a splitter to connect to two RF ports of the DUT corresponding to the two antennas of interest. In the setups, power meter is used to tap the directional coupler for measuring the conducted output power of the DUT. For all conducted tests, only RF1 COM port of the callbox is used to communicate with the DUT.

All the path losses from RF port of DUT to the callbox RF COM port and to the power meter are calibrated and automatically entered as offsets in the callbox and the power meter via test scripts on the PC used to control callbox and power meter.



(b) Appendix D – Test Setup Photo 2

Figure 6-1 Conducted power measurement setup

	FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:		Dage 16 of 15
	1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 16 of 45
0	2020 PCTEST				REV 1.0

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Both the callbox and power meter are connected to the PC using GPIB cables. Two test scripts are custom made for automation, and the test duration set in the test scripts is 500 seconds.

For time-varying Tx power measurement, the PC runs the 1<sup>st</sup> test script to send GPIB commands to control the callbox's requested power versus time, while at the same time to record the conducted power measured at DUT RF port using the power meter. The commands sent to the callbox to request power are:

- 0dBm for 100 seconds
- test sequence 1 or test sequence 2 (defined in Section 5.1 and generated in Section 5.2.1), for 360 seconds
- stay at the last power level of test sequence 1 or test sequence 2 for the remaining time.

Power meter readings are periodically recorded every 100ms. A running average of this measured Tx power over 100 seconds is performed in the post-data processing to determine the 100s-time averaged power.

For call drop, technology/band/antenna switch, and DSI switch tests, after the call is established, the callbox is set to request the DUT's Tx power at 0dBm for 100 seconds while simultaneously starting the 2<sup>nd</sup> test script runs at the same time to start recording the Tx power measured at DUT RF port using the power meter. After the initial 100 seconds since starting the Tx power recording, the callbox is set to request maximum power from the DUT for the rest of the test. Note that the call drop/re-establish, or technology/band/antenna switch or DSI switch is manually performed when the Tx power of DUT is at Preserve level. See Section 5.3 for detailed test procedure of call drop test, technology/band/antenna switch test and DSI switch test.

#### 6.2 SAR Measurement setup

The measurement setup is similar to normal SAR measurements as described in the Part 1 Test Report. The difference in SAR measurement setup for time averaging feature validation is that the callbox is signaling in close loop power control mode (instead of requesting maximum power in open loop control mode) and callbox is connected to the PC using GPIB so that the test script executed on PC can send GPIB commands to control the callbox's requested power over time (test sequence). The same test script used in conducted setup for time-varying Tx power measurements is also used in this section for running the test sequences during SAR measurements, and the recorded values from the disconnected power meter by the test script were discarded.

As mentioned in Section 5.4, for DUT to follow TPC command sent from the callbox wirelessly, the "path loss" between callbox antenna and the DUT needs to be very well calibrated. Since the SAR chamber is in uncontrolled environment, precautions must be taken to minimize the environmental influences on "path loss".

The DUT is placed in worst-case position according to Table 7-2.

FCC ID: A3LSMG986JPN	Froud to be part of element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 17 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 17 of 45
© 2020 PCTEST				REV 1.0

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# 7 TEST CONFIGURATIONS

### 7.1 WWAN (sub-6) transmission

The  $P_{limit}$  values, corresponding to 1.0 W/kg (1gSAR) and 2.5 W/kg (10gSAR) of *SAR\_design\_target*, for technologies and bands supported by DUT are derived in Part 0 report and summarized in Table 7-1. Note all  $P_{limit}$  power levels entered in Table 7-1 correspond to average power levels after accounting for duty cycle in the case of TDD modulation schemes (for e.g., GSM, LTE TDD).

Exposure Scenari	o:	Body-Worn	Phablet	Phablet	Head	Hotspot	Phablet	
Averaging Volume:		1g	10g	10g	1g	1g	10g	Maximum Tune-up
Spacing:		15 mm	6, 8, 11 mm	0 mm	0 mm	10 mm	0 mm	Output Power*
DSI:		0	0	1	2	3	4	
Technology/Band	Antenna	Plimit co	orresponding	to 1W/kg / 2.	5 W/kg (1g/1	Og SAR_desigr	n_target)	Pmax
GSM/GPRS/EDGE 850 MHz	A	31.2	31.2	29.6	32.3	29.6	29.6	24.8
GSM/GPRS/EDGE 1900 MHz	A	26.1	26.1	18.8	34.0	18.8	18.8	21.3
UMTS B5	A	30.5	30.5	26.8	31.4	26.8	26.8	23.0
LTE FDD B12	A	31.3	31.3	29.2	33.6	29.2	29.2	23.0
LTE FDD B13	A	30.4	30.4	27.4	31.7	27.4	27.4	23.0
LTE FDD B5	A	31.0	31.0	27.0	31.6	27.0	27.0	23.0
LTE FDD B4	A	25.0	25.0	19.5	31.6	19.5	19.5	22.5
LTE TDD B41	В	27.3	27.3	21.5	33.1	19.0	21.5	22.0

Table 7-1 $P_{limit}$  for supported technologies and bands ( $P_{limit}$  in EFS file)

\* Maximum tune up target power,  $P_{max}$ , is configured in NV settings in DUT to limit maximum transmitting power. This power is converted into peak power in NV settings for TDD schemes. The DUT maximum allowed output power is equal to  $P_{max}$  + 1 dB device uncertainty.

Based on selection criteria described in Section 5.2.1, the selected technologies/bands for testing time-varying test sequences are highlighted in yellow in Table 7-1. Per the manufacturer, the *Reserve\_power\_margin* (dB) is set to 3dB in EFS, and is used in Part 2 test.

The radio configurations used in Part 2 test for selected technologies, bands, DSIs and antennas are listed in Table 7-2. The corresponding worst-case radio configuration 1gSAR or 10gSAR values for selected technology/band/DSI are extracted from Part 1 report and are listed in the last column of Table 7-2.

Based on equations (1a), (2a), (3a) and (4a), it is clear that Part 2 testing outcome is normalized quantity, which implies that it can be applied to any radio configuration within a selected technology/band/DSI. Thus, as long as applying the worst-case SAR obtained from the worst radio configuration in Part 1 testing to calculate time-varying SAR exposure in equations (1a), (2a), (3a) and (4a), the accuracy in compliance demonstration remains the same. Therefore, there may be some differences between the radio configuration selected for Part 2 testing and the radio configuration associated with worst-case SAR obtained in the Part 1 evaluation.

FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates: DUT Type:				
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 18 of 45	
© 2020 PCTEST				REV 1 0	

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Test Case #	Test Scenario	Tech	Band	Antenna	DSI	Channel	Frequency [MHz]	RB/RB Offset/Bandwidth (MHz)	Mode	SAR Exposure Scenario	Part 1 worst Case Measured SAR at Plimit (W/kg)
1	Test Sequence 1		B4	А	3	20175	1732.5	1/50/20 MHz BW	QPSK	Hotspot, bottom edge, 10 mm	1.080
2	Test Sequence 2	LTE	D4	A	3	20175	1732.5	1/50/20 MHz BW	QPSK	Hotspot, bottom edge, To min	1.080
3	Test Sequence 1		B41	в	3	39750	2506	1/0/20 MHz BW	QPSK	Hotopot bottom odgo 10 mm	0.768
4	Test Sequence 2	Ī	B41	в	3	39750	2506	1/0/20 MHz BW	QPSK	Hotspot, bottom edge, 10 mm	0.700
5	Test Sequence 1	GPRS	1900	А	3	810	1909.8	-	GPRS, 4 Tx	University hottom a day, 40 mm	0.782
6	Test Sequence 2	GPRS	1900	А	3	810	1909.8	-	GPRS, 4 Tx	Hotspot, bottom edge, 10 mm	0.782
7	Change in Call	GPRS	1900	Α	3	810	1909.8	-	GPRS, 4 Tx	Hotspot, bottom edge, 10 mm	0.782
8	Tech/Band Switch	LTE	B4	Α	3	20175	1732.5	1/50/20 MHz BW	QPSK	Hotspot, bottom edge, 10 mm	1.080
•	Tech/Band Switch	GPRS	1900	A	3	810	1909.8	-	GPRS, 4 Tx	Hotspot, bottom edge, 10 mm	0.782
9	Antenna Switch	LTE	B41	В	3	39750	2506	1/0/20 MHz BW	QPSK	Hotspot, bottom edge, 10 mm	0.768
9	Antenna Switch	LIC	B4	A	3	20175	1732.5	1/50/20 MHz BW	QPSK	Hotspot, bottom edge, 10 mm	1.080
10	DSI Switch	LTE	B41	В	3	39750	2506	1/0/20 MHz BW	QPSK	Hotspot, bottom edge, 10 mm	0.768
10	Doi SWITCH	LIE	D41	В	1	39750	2506	1/0/20 MHz BW	QPSK	Phablet, Bottom Edge, 0 mm	2.67*

#### Table 7-2 Radio configurations selected for Part 2 test

\*Indicates 10g SAR

Note that the DUT has a proximity sensor to manage extremity exposure, which is represented using DSI = 1; the head exposure can be distinguished through audio receiver mode, represented as DSI = 2; similarly, the hotspot exposure is distinguished via hotspot mode, represented as DSI = 3; the exposure for headset jack active scenario is represented using DSI = 4 and is managed as the same exposure condition as extremity exposure at 0 mm; DSI = 0represents all other exposures which cannot be distinguished, thus, in this case, the maximum 1gSAR and/or 10gSAR among all remaining exposure scenarios or the minimum *Plimit* among all remaining exposure scenarios (i.e., body worn 1gSAR evaluation at 15mm spacing, phablet 10gSAR extremity evaluation at 6~11mm spacing, phablet 10gSAR extremity evaluation at Omm spacing for left and right surfaces) is used in Smart Transmit feature for time averaging operation.

Based on the selection criteria described in Section 5.2, the radio configurations for the Tx varying transmission test cases listed in Section 4 are:

- 1. Technologies and bands for time-varying Tx power transmission: The test case 1~6 listed in Table 7-2 are selected to test with the test sequences defined in Section 5.1 in both timevarying conducted power measurement and time-varying SAR measurement.
- 2. Technology and band for change in call test: GSM/GPRS/EDGE 1900 having the lowest Plimit among all technologies and bands (test case 7 in Table 7-2) is selected for performing the call drop test in conducted power setup.
- 3. Technologies and bands for change in technology/band test: Following the guidelines in Section 5.2.3, test case 8 in Table 7-2 is selected for handover test from a technology/band within one technology group (LTE Band 4, DSI=3, antenna A), to a technology/band in the same DSI within another technology group (GSM/GPRS/EDGE 1900, DSI=3, antenna A) in conducted power setup.
- 4. Technologies and bands for change in antenna: Based on selection criteria in Section 5.2.4, for a given DSI=3, test case 9 in Table 7-2 is selected for time window switch between Antenna B (LTE 41, AntennaB) and Antenna A (LTE 4, Antenna A) in conducted power setup.
- 5. Technologies and bands for change in DSI: Based on selection criteria in Section 5.2.5, for a given technology and band, test case 10 in Table 7-2 is selected for DSI switch test by establishing a call in LTE Band 41 in DSI=3, and then handing over to DSI = 1 exposure scenario in conducted power setup.

FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 10 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 19 of 45
© 2020 PCTEST				REV 1.0

#### 7.2 *Plimit* and *Pmax* measurement results

The measured *P*<sub>limit</sub> for all the selected radio configurations given in Table 7-2 are listed in below Table 7-3. *P<sub>max</sub>* was also measured for radio configurations selected for testing time-varying Tx power transmission scenarios in order to generate test sequences following the test procedures in Section 5.1.

Test Case #	Test Scenario	Tech	Band	Antenna	DSI	Channel	Frequency [MHz]	RB/RB Offset/Bandwidth (MHz)	Mode	SAR Exposure Scenario	EFS Plimit [dBm]	Tune-up Pmax [dBm]	Measured Plimit [dBm]	Measured Pmax [dBm]			
1	Test Sequence 1		B4	А	2	20175	1732.5	1/50/20 MHz BW	QPSK	Hotspot, bottom edge,	19.5	22.5	20.14	23.13			
2	Test Sequence 2	LTE	D4	~	3	20175	1732.5	1/50/20 MHz BW	QPSK	10 mm	19.5	22.5	20.14	23.13			
3	Test Sequence 1		B41	в	2	39750	2506	1/0/20 MHz BW	QPSK	Hotspot, bottom edge,	19.0	22.0	19.47	21.82			
4	Test Sequence 2		D41	Р	3	39750	2506	1/0/20 MHz BW	QPSK	10 mm	19.0	22.0	19.47	21.82			
5	Test Sequence 1	GPRS	1900	А	2	810	1909.8	-	GPRS, 4 Tx	Hotspot, bottom edge,	18.8	20.3	19.13	20.28			
6	Test Sequence 2	GFRG	1900	^	3	810	1909.8		GPRS, 4 Tx	10 mm	18.8	20.3	19.13	20.28			
7	Change in Call	GPRS	1900	A	3	810	1909.8	-	GPRS, 4 Tx	-	18.8	20.3	19.13	20.28			
8	Tech/Band Switch	LTE	B4	A	3	20175	1732.5	1/50/20 MHz BW	QPSK		19.5	22.5	20.14	23.13			
•	Tech/Band Switch	GPRS	1900	A	3	810	1909.8	-	GPRS, 4 Tx	-	18.8	20.3	19.13	20.28			
9	Antenna Switch	LTE	B41	В	3	39750	2506	1/0/20 MHz BW	QPSK		19.0	22.0	19.47	21.82			
9	Antenna Switch		B4	A	3	20175	1732.5	1/50/20 MHz BW	QPSK	-	19.5	22.5	20.14	23.13			
40	DCI Cuitate	1 TF	B41	В	3	39750	2506	1/0/20 MHz BW	QPSK	-	19.0	22.0	19.47	21.82			
10	10 DSI Switch L	LIE	LIE	LTE	LIE	D41	В	1	39750	2506	1/0/20 MHz BW	QPSK	-	21.5	22.0	21.93	21.82

Table 7-3 Measured *P*<sub>limit</sub> and *P*<sub>max</sub> of selected radio configurations

Note: The device uncertainty of  $P_{max}$  is +/- 1 dB as provided by manufacturer.

Note: The above Pmax value for GPRS1900 is for 4 Tx Slots

FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @element	PART 2 RF EXPOSURE EVALUATION REPORT	<b>SAMSUNG</b>	Approved by: Quality Manager	
Document S/N:	ment S/N: Test Dates: DUT Type:				
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 20 of 45	
© 2020 PCTEST				REV 1.0	

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#### 8 CONDUCTED TX CASES

#### 8.1 Time-varying Tx Power Case

The measurement setup is shown in Figure 6-1. The purpose of the time-varying Tx power measurement is to demonstrate the effectiveness of power limiting enforcement and that the time-averaged Tx power when represented in time-averaged 1gSAR or 10gSAR values does not exceed FCC limit as shown in Eq. (1a) and (1b), rewritten below:

$$1g\_or\_10gSAR(t) = \frac{conducted\_Tx\_power(t)}{conducted\_Tx\_power\_P_{limit}} * 1g\_or\_10gSAR\_P_{limit}$$
(1a)

$$\frac{\frac{1}{T_{SAR}}\int_{t-T_{SAR}}^{t} 1g_{or_{-}10gSAR(t)dt}}{FCC\,SAR\,limit} \le 1$$
(1b)

where,  $conducted_Tx_power(t)$ ,  $conducted_Tx_power_P_{limit}$ , and  $1g_or_10gSAR_P_{limit}$ correspond to the measured instantaneous conducted Tx power, measured conducted Tx power at Plimit, and measured 1gSAR and 10gSAR values at Plimit reported in Part 1 test (listed in Table 7-2 of this report as well).

Following the test procedure in Section 5.3, the conducted Tx power measurement for all selected configurations are reported in this section. In all the conducted Tx power plots, the dotted line represents the requested power by callbox (test sequence 1 or test sequence 2), the blue curve represents the instantaneous conducted Tx power measured using power meter, the green curve represents time-averaged power and red line represents the conducted power limit that corresponds to FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.

Similarly, in all the 1g or 10gSAR plots (when converted using Eq. (1a)), the green curve represents the 100s/60s-time averaged 1gSAR or 10gSAR value calculated based on instantaneous 1gSAR or 10gSAR; and the red line limit represents the FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.

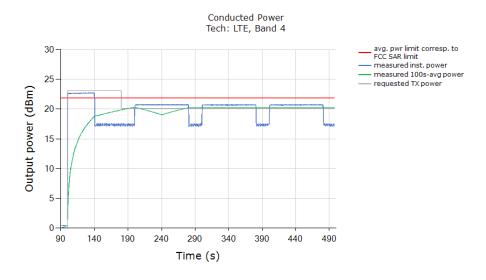
Time-varying Tx power measurements were conducted on test cases  $\#1 \sim \#6$  in Table 7-2, by generating test sequence 1 and test sequence 2 given in APPENDIX E: using measured Plimit and measured P<sub>max</sub> (last two columns of Table 7-3) for each of these test cases. Measurement results for test cases #1 ~ #6 are given in Sections 8.1.1-8.1.3.

FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	est Dates: DUT Type:			
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 21 of 45	
© 2020 PCTEST				REV 1.0	

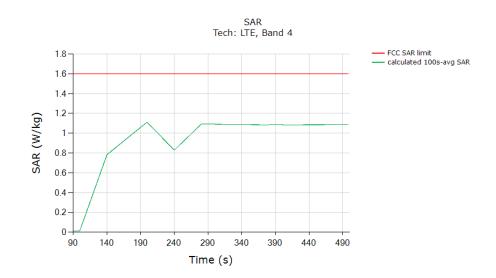
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Test result for test sequence 1:



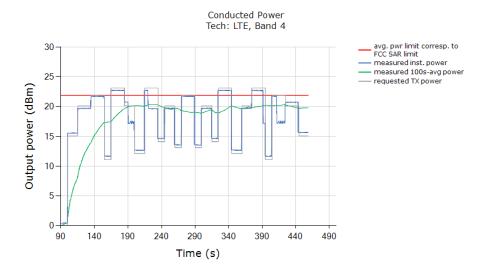
Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:



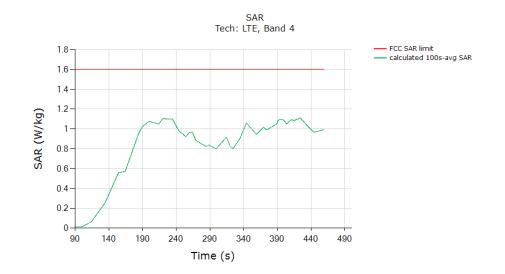
	(W/kg)			
FCC 1gSAR limit	1.6			
Max 100s-time averaged 1gSAR (green curve)	1.110			
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of measured SAR at <i>P</i> <sub>limit</sub> (last column in Table 7-2).				

FCC ID: A3LSMG986JPN	PCTEST <sup>*</sup> Proud to be part of <b>®</b> element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	Dage 22 of 45		
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 22 of 45
© 2020 PCTEST				REV 1.0

#### Test result for test sequence 2:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:



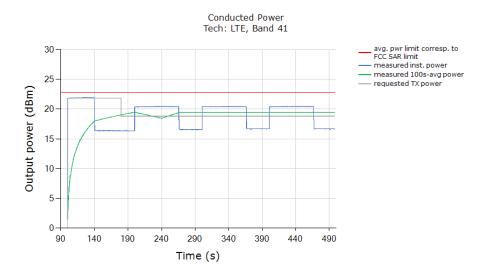
	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	1.110
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>P</i> <sub>limit</sub> (last column in Table 7-2).	nty of measured

FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:			
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 23 of 45	
© 2020 PCTEST				REV 1.0	

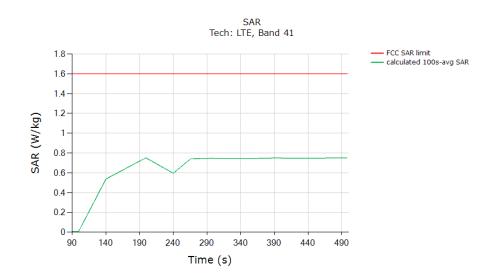
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Test result for test sequence 1:



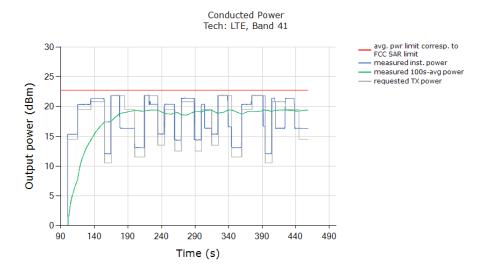
Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:



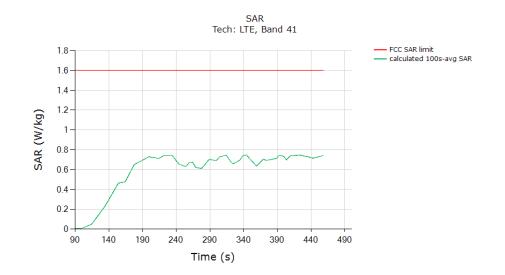
	(W/kg)			
FCC 1gSAR limit	1.6			
Max 100s-time averaged 1gSAR (green curve)	0.751			
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of measured SAR at <i>P</i> <sub>limit</sub> (last column in Table 7-2).				

FCC ID: A3LSMG986JPN	Froud to be part of element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 24 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 24 of 45
© 2020 PCTEST				REV 1.0

#### Test result for test sequence 2:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:



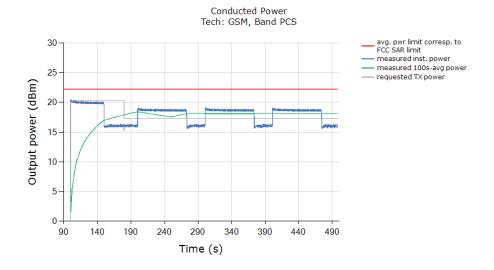
	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.747
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>P</i> <sub>limit</sub> (last column in Table 7-2).	nty of measured

FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 25 of 45
© 2020 PCTEST				REV 1.0

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8.1.3

#### Test result for test sequence 1:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

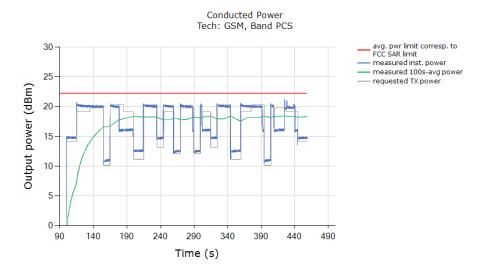


	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.667
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>P</i> <sub>limit</sub> (last column in Table 7-2).	ty of measured

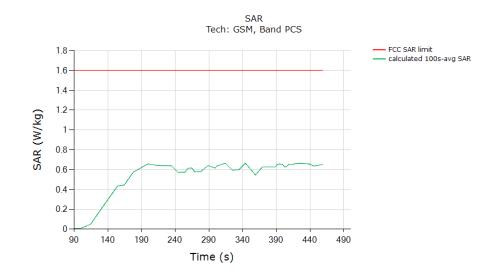
FCC ID: A3LSMG986JPN	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 26 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 26 of 45
© 2020 PCTEST				REV 1.0

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#### Test result for test sequence 2:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:



	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.664
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>P</i> <sub>limit</sub> (last column in Table 7-2).	nty of measured

FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dawa 07 af 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 27 of 45
© 2020 PCTEST				REV 1.0

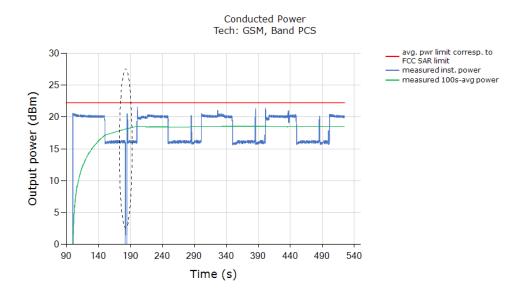
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#### 8.2 **Call Drop Test Case**

This test was measured with GSM/GPRS/EDGE 1900, Antenna 3, DSI=3, and with callbox requesting maximum power. The call drop was manually performed when the DUT is transmitting at Preserve level as shown in the plot below (dotted black region). The measurement setup is shown in Figure 6-1. The detailed test procedure is described in Section 5.3.2.

#### Call drop test result:

Plot 1: Measured Tx power (dBm) versus time shows that the transmitting power kept the same Preserve level of GSM/GPRS/EDGE 1900 after the call was re-established:

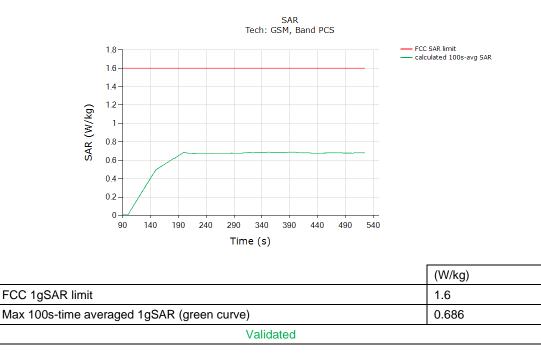


Plot Notes: The power level after the change in call kept the same Preserve level of GSM/GPRS/EDGE 1900. The conducted power plot shows expected Tx transition.

FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Daga 20 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 28 of 45
© 2020 PCTEST				REV 1.0

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Plot 2: Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:



The test result validated the continuity of power limiting in call change scenario.

#### 8.3 Change in Technology/Band Test Case

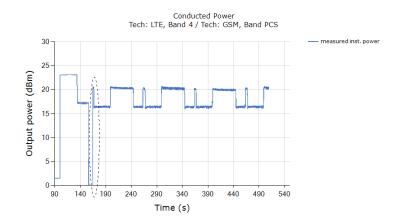
This test was conducted with callbox requesting maximum power, and with a technology switch from LTE 4, Antenna A, DSI = 3 to GSM/GPRS/EDGE 1900, Antenna A, DSI = 3. Following procedure detailed in Section 5.3.3, and using the measurement setup shown in Figure 6-1, the technology/band switch was performed when the DUT is transmitting at Preserve level as shown in the plot below (dotted black region).

#### Test result for change in technology/band:

Plot 1: Measured Tx power (dBm) versus time shows that the transmitting power changed from LTE 4, Antenna A, DSI = 3 Preserve level to GSM/GPRS/EDGE 1900, Antenna A, DSI = 3 Preserve level (within 1 dB device uncertainty):

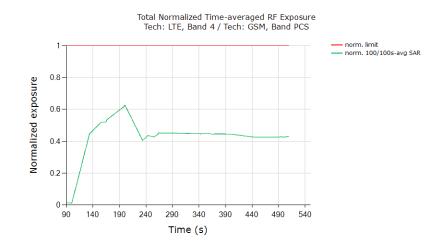
FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 20 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 29 of 45
© 2020 PCTEST				REV 1.0

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Note: As per Part 1 report, Reserve\_power\_margin = 3dB. Based on Table 7-1, EFS Plimit = 19.5dBm for LTE B4 (DSI=3), and EFS Plimit = 18.8 dBm for GSM/GPRS/EDGE 1900 (DSI=3), it can be seen from above plot that the difference in Preserve (= Plimit – 3dB Reserve\_power\_margin) power level corresponds to the expected difference in Plimit levels of 0.7dB (within 1dB of sub6 radio design related uncertainty). Therefore, the conducted power plot shows expected transition in Tx power.

Plot 2: All the time-averaged conducted Tx power measurement results were converted into time-averaged normalized SAR values using Equation (6a), (6b) and (6c), and plotted below to demonstrate that the time-averaged normalized SAR versus time does not exceed the normalized FCC limit of 1.0:



	(W/kg)
FCC normalized SAR limit	1.0
Max 100s-time averaged normalized SAR (green curve)	0.627
Validated	

#### The test result validated the continuity of power limiting in technology/band switch scenario.

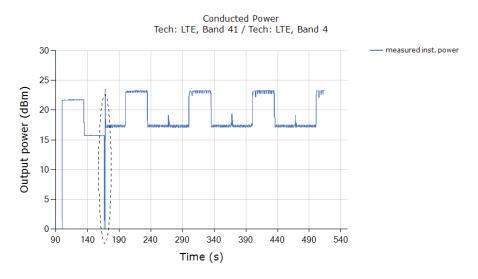
FCC ID: A3LSMG986JPN	PCTEST <sup>*</sup> Proud to be part of <b>®</b> element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 20 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 30 of 45
© 2020 PCTEST				REV 1.0

#### 8.4 **Change in Antenna Test Case**

This test was conducted with callbox requesting maximum power, and with an antenna switch from LTE 41, Antenna B, DSI = 3 to LTE 4, Antenna A, DSI = 3. Following procedure detailed in Section 5.3.3, and using the measurement setup shown in Figure 6-1, the technology/band switch was performed when the DUT is transmitting at Preserve level as shown in the plot below (dotted black region).

#### Test result for change in technology/band:

Plot 1: Measured Tx power (dBm) versus time shows that the transmitting power changed from LTE 41, Antenna B, DSI = 3 Preserve level to LTE Band 4, Antenna A, DSI = 3 Preserve level (within 1 dB device uncertainty):

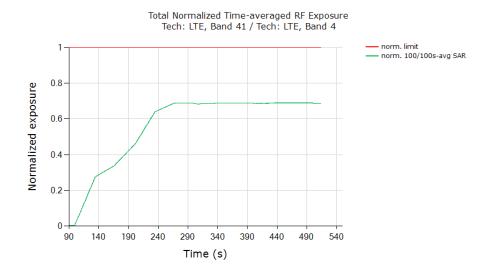


Note: As per Part 1 report, Reserve\_power\_margin = 3dB. Based on Table 7-1, EFS Plimit = 19.0dBm for LTE B41 (DSI=3), and 19.5dBm for LTE B4 (DSI=3), it can be seen from above plot that the difference in Preserve (= Plimit – 3dB Reserve\_power\_margin) power level corresponds to the expected difference in *Plimit* levels of 0.5 dB (within 1dB of sub6 radio design related uncertainty). Therefore, the conducted power plot shows expected transition in Tx power.

FCC ID: A3LSMG986JPN		PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 21 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 31 of 45
© 2020 PCTEST				REV 1.0

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Plot 2: All the time-averaged conducted Tx power measurement results were converted into time-averaged normalized SAR values using Equation (6a), (6b) and (6c), and plotted below to demonstrate that the time-averaged normalized SAR versus time does not exceed the normalized FCC limit of 1.0:



	(W/kg)
FCC normalized SAR limit	1.0
Max 100s-time averaged normalized SAR (green curve)	0.691
Validated	

The test result validated the continuity of power limiting in technology/band switch scenario.

#### 8.5 **DSI Switch Test Case**

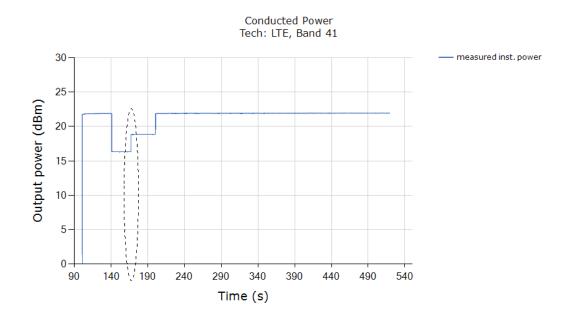
This test was conducted with callbox requesting maximum power, and with DSI switch from LTE 41 DSI = 3 (hotspot) to DSI = 1 (grip sensor triggered). Following procedure detailed in Section 5.3.5 using the measurement setup shown in Figure 6-1, the DSI switch was performed when the DUT is transmitting at Preserve level as shown in the plot below (dotted black circle).

Test result for change in DSI:

Plot 1: Measured Tx power (dBm) versus time shows that the transmitting power changed when DSI = 3 switches to DSI = 1:

FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 22 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 32 of 45
© 2020 PCTEST				REV 1.0

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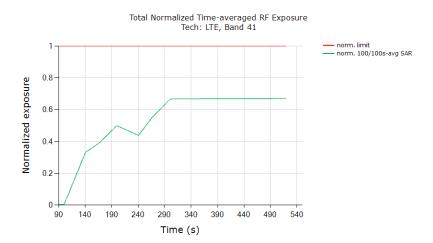


Note: As per Part 1 report, Reserve\_power\_margin = 3dB. Based on Table 7-1, EFS Plimit = 19.0 dBm for LTE B41 hotspot DSI = 3, and EFS Plimit = 21.5dBm for extremity DSI = 1.The difference in Preserve (= Plimit - 3dB Reserve\_power\_margin) level corresponds to the expected different in Plimit levels of 2.5 dB (within 1dB of sub6 radio design related uncertainty). Therefore, the conducted power plot shows expected transition in Tx power.

FCC ID: A3LSMG986JPN	PCTEST* Froud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Dage 22 of 45			
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 33 of 45
© 2020 PCTEST				REV 1.0

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Plot 2: All the time-averaged conducted Tx power measurement results were converted into timeaveraged normalized SAR values using Equation (6a), (6b) and (6c), and plotted below to demonstrate that the time-averaged normalized SAR versus time does not exceed the FCC limit of 1 unit.



	(W/kg)
FCC normalized total exposure limit	1.0
Max 100s-time averaged normalized SAR (green curve)	0.670
Validated	

The test result validated the continuity of power limiting in DSI switch scenario.

FCC ID: A3LSMG986JPN	PCTEST* Froud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates: DUT Type:				
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 34 of 45	
© 2020 PCTEST				REV 1.0	

# **9** SYSTEM VERIFICATION

### 9.1 **Tissue Verification**

Calibrated for Tests Performed on:	Tissue Type	Tissue Temp During Calibration (°C)	Measured Frequency (MHz)	Measured Conductivity, σ (S/m)	Measured Dielectric Constant, ε	TARGET Conductivity, σ (S/m)	TARGET Dielectric Constant, ε	%devσ	%devε
			1710	1.430	51.272	1.463	53.537	-2.26%	-4.23%
04/01/2020	1750B	21.1	1750	1.457	51.209	1.488	53.432	-2.08%	-4.16%
			1790	1.485	51.140	1.514	53.326	-1.92%	-4.10%
			1850	1.527	51.037	1.520	53.300	0.46%	-4.25%
04/01/2020	1900B	21.1	1880	1.547	50.988	1.520	53.300	1.78%	-4.34%
			1910	1.567	50.944	1.520	53.300	3.09%	-4.42%
			2300	1.883	50.474	1.809	52.900	4.09%	-4.59%
		B 21.1	2310	1.892	50.461	1.816	52.887	4.19%	-4.59%
			2320	1.900	50.451	1.826	52.873	4.05%	-4.58%
			2400	1.973	50.321	1.902	52.767	3.73%	-4.64%
			2450	2.017	50.255	1.950	52.700	3.44%	-4.64%
			2500	2.066	50.181	2.021	52.636	2.23%	-4.66%
04/01/2020	2450B		2510	2.075	50.170	2.035	52.623	1.97%	-4.66%
04/01/2020		21.1	2535	2.099	50.138	2.071	52.592	1.35%	-4.67%
			2550	2.113	50.109	2.092	52.573	1.00%	-4.69%
			2560	2.123	50.089	2.106	52.560	0.81%	-4.70%
			2600	2.165	50.028	2.163	52.509	0.09%	-4.72%
			2650	2.214	49.929	2.234	52.445	-0.90%	-4.80%
			2680	2.245	49.868	2.277	52.407	-1.41%	-4.84%
			2700	2.265	49.835	2.305	52.382	-1.74%	-4.86%

Table 9-1 Measured Tissue Properties

The above measured tissue parameters were used in the DASY software. The DASY software was used to perform interpolation to determine the dielectric parameters at the SAR test device frequencies (per KDB Publication 865664 D01v01r04 and IEEE 1528-2013 6.6.1.2). The tissue parameters listed in the SAR test plots may slightly differ from the table above due to significant digit rounding in the software.

FCC ID: A3LSMG986JPN	PCTEST <sup>®</sup> Froud to be part of <sup>®</sup> element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 25 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 35 of 45
© 2020 PCTEST				REV 1.0

REV 1.0 04/06/2020

### 9.2 Test System Verification

Prior to SAR assessment, the system is verified to  $\pm 10\%$  of the SAR measurement on the reference dipole at the time of calibration by the calibration facility. Full system validation status and result summary can be found in Appendix C.

	System Verification TARGET & MEASURED											
SAR System #	Tissue Frequency (MHz)	Tissue Type	Date	Amb. Temp (°C)	Liquid Temp (°C)	Input Power (W)	Source SN	Probe SN	Measured SAR1g (W/kg)	1 W Target SAR <sub>1g</sub> (W/kg)	1 W Normalized SAR1g (W/kg)	Deviation <sub>1g</sub> (%)
L	1750	BODY	04/01/2020	22.0	21.1	0.100	1008	7410	3.890	37.400	38.900	4.01%
L	1900	BODY	04/01/2020	22.0	21.1	0.100	5d148	7410	4.260	39.100	42.600	8.95%
L	2450	BODY	04/01/2020	22.0	21.1	0.100	719	7410	5.280	50.800	52.800	3.94%
L	2600	BODY	04/01/2020	22.0	21.1	0.100	1064	7410	5.580	55.600	55.800	0.36%

Table 9-2 System Verification Results – 1g

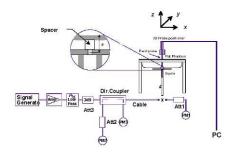


Figure 9-1 System Verification Setup Diagram



Figure 9-2 System Verification Setup Photo

FCC ID: A3LSMG986JPN	PCTEST Froud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 20 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 36 of 45
© 2020 PCTEST				REV 1.0

REV 1.0 04/06/2020

#### 10 SAR TEST RESULTS FOR SMART TRANSMIT VALIDATION

### 10.1 Time-varying Tx Power Case

Following Section 5.4 procedure, time-averaged SAR measurements are conducted using a SAR probe at peak location of area scan over 500 seconds. cDASY6 system verification for SAR measurement is provided in Section 9, and the associated SPEAG certificates are attached in Appendix F.

SAR probe integration times depend on the communication signal being tested as defined in the probe calibration parameters.

Since the sampling rate used by cDASY6 for pointSAR measurements is not in user control, the number of points in 100s interval is determined from the scan duration setting in cDASY6 timeaverage pointSAR measurement by (100s cDASY6\_scan\_duration \* total number of pointSAR values recorded). Running average is performed over these number of points in excel spreadsheet to obtain 100s averaged pointSAR.

Following Section 5.4, for each of selected technology/band (listed in Table 7-2):

- 6. With Reserve power margin set to 0 dB, area scan is performed at Plimit, and time-averaged pointSAR measurements are conducted to determine the pointSAR at *P*<sub>limit</sub> at peak location, denoted as *point*SAR<sub>Plimit</sub>.
- 7. With Reserve power margin set to actual (intended) value, two more time-averaged pointSAR measurements are performed at the same peak location for test sequences 1 and 2.

To demonstrate compliance, all the pointSAR measurement results were converted into 1gSAR or 10gSAR values by using Equation (3a), rewritten below:

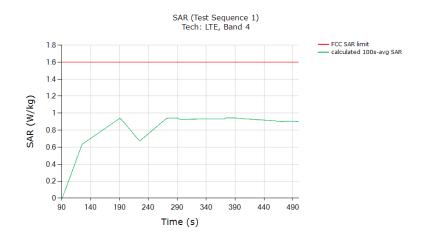
$$1g_or_10gSAR(t) = \frac{pointSAR(t)}{pointSAR_{limit}} * 1g_or_10gSAR_{limit}$$
(3a)

where, pointSAR(t),  $pointSAR_{P_{limit}}$ , and  $1g_{or}_{10}gSAR_{P_{limit}}$  correspond to the measured instantaneous point SAR, measured point SAR at Plimit from above step 1 and 2, and measured 1gSAR or 10gSAR values at Plimit obtained from Part 1 report and listed in Table 7-2 of this report.

FCC ID: A3LSMG986JPN		PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 37 of 45
© 2020 PCTEST		·		REV 1.0

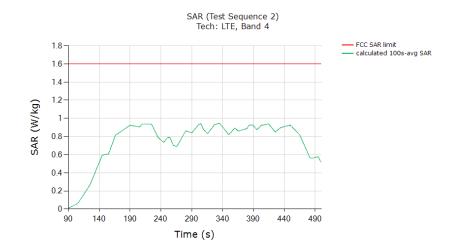
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### SAR test results for test sequence 1:



	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged point 1gSAR (green curve)	0.943
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertair SAR at <i>P</i> <sub>limit</sub> (last column in Table 7-2).	nty of measured

### SAR test results for test sequence 2:



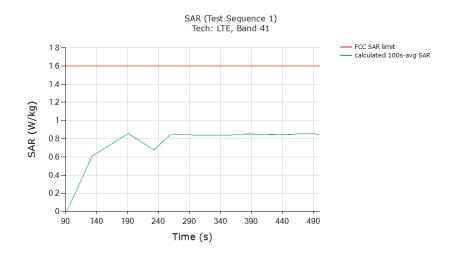
	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.945
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>P</i> <sub>limit</sub> (last column in Table 7-2).	nty of measured

FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 28 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 38 of 45
© 2020 PCTEST	·	•		REV 1.0

© 2020 PCTEST

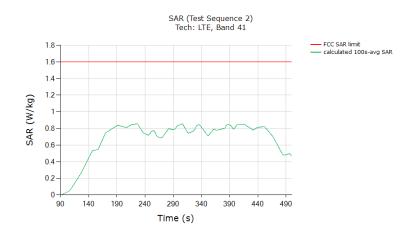
#### 10.1.2 LTE Band 41

### SAR test results for test sequence 1:



	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged point 1gSAR (green curve)	0.858
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>P</i> <sub>limit</sub> (last column in Table 7-2).	nty of measured

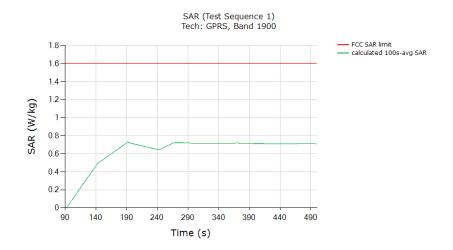
### SAR test results for test sequence 2:



	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.855
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>P</i> <sub>limit</sub> (last column in Table 7-2).	nty of measured

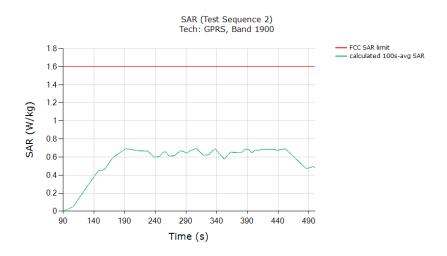
FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dawa 20 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 39 of 45
© 2020 PCTEST				REV 1.0

### SAR test results for test sequence 1:



	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged point 1gSAR (green curve)	0.727
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>Plimit</i> (last column in Table 7-2).	nty of measured

### SAR test results for test sequence 2:



	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.693
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>P</i> <sub>limit</sub> (last column in Table 7-2).	nty of measured

	FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:		Page 40 of 45
	1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 40 01 45
0	2020 PCTEST				REV 1.0

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#### 11 EQUIPMENT LIST

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
Agilent	8594A	(9kHz-2.9GHz) Spectrum Analyzer	N/A	N/A	N/A	3051A00187
Agilent	E4432B	ESG-D Series Signal Generator	7/14/2019	Annual	7/14/2020	US40053896
Agilent	N9020A	MXA Signal Analyzer	4/20/2019	Annual	4/20/2020	US46470561
Agilent	N5182A	MXG Vector Signal Generator	6/27/2019	Annual	6/27/2020	US46240505
Agilent	8753ES	S-Parameter Network Analyzer	12/31/2019	Annual	12/31/2020	US39170122
Agilent	N5182A	MXG Vector Signal Generator	7/10/2019	Annual	7/10/2020	MY47420800
Agilent	E4438C	ESG Vector Signal Generator	3/8/2019	Biennial	3/8/2021	MY42082385
Agilent	E4438C	ESG Vector Signal Generator	3/11/2019	Biennial	3/11/2021	MY45090700
Agilent	8753ES	S-Parameter Network Analyzer	1/16/2020	Annual	1/16/2021	US39170118
Agilent	8753ES	S-Parameter Network Analyzer	8/26/2019	Annual	8/26/2020	MY40000670
Agilent	8753ES	S-Parameter Vector Network Analyzer	9/19/2019	Annual	9/19/2020	MY40003841
Amplifier Research	15S1G6	Amplifier	CBT	N/A	CBT	433972
Amplifier Research	155166	Amplifier	CBT	N/A	CBT	433974
Anritsu	ML2495A	Power Meter	12/17/2019	Annual	12/17/2020	941001
	MA24106A					
Anritsu		USB Power Sensor	5/6/2019	Annual	5/6/2020	1231538
Anritsu	MA24106A	USB Power Sensor	5/22/2019	Annual	5/22/2020	1231535
Anritsu	MA24106A	USB Power Sensor	6/21/2019	Annual	6/21/2020	1244515
Anritsu	ML2496A	Power Meter	12/17/2019	Annual	12/17/2020	1138001
Anritsu	MA2411B	Pulse Power Sensor	6/11/2019	Annual	6/11/2020	1207364
Anritsu	MA2411B	Pulse Power Sensor	12/4/2019	Annual	12/4/2020	1126066
COMTECH	AR85729-5/5759B	Solid State Amplifier	CBT	N/A	CBT	M3W1A00-1002
COMTech	AR85729-5	Solid State Amplifier	CBT	N/A	CBT	M1S5A00-009
Control Company	4352	Ultra Long Stem Thermometer	8/2/2018	Biennial	8/2/2020	181292054
Control Company	4352	Ultra Long Stem Thermometer	8/2/2018	Biennial	8/2/2020	181292061
Control Company	4040	Therm./ Clock/ Humidity Monitor	10/9/2018	Biennial	10/9/2020	181647811
Control Company	4040	Therm./ Clock/ Humidity Monitor	10/9/2018	Biennial	10/9/2020	181647802
Control Company	4040	Therm./ Clock/ Humidity Monitor	10/9/2018	Biennial	10/9/2020	181647812
Control Company	4352	Long Stem Thermometer	6/26/2019	Biennial	6/26/2021	192282745
Control Company	4352	Long Stem Thermometer	6/26/2019	Biennial	6/26/2021	192282753
Keysight	772D	Dual Directional Coupler	CBT	N/A	CBT	MY52180215
eysight Technologies	N6705B	DC Power Analyzer	4/27/2019	Biennial	4/27/2021	MY53004059
MCL	BW-N6W5+	6dB Attenuator	4/2//2019 CBT	N/A	4/2//2021 CBT	1139
	SLP-2400+		CBT	N/A	CBT	R8979500903
MiniCircuits		Low Pass Filter				
MiniCircuits	VLF-6000+	Low Pass Filter	CBT	N/A	CBT	N/A
Mini-Circuits	BW-N20W5+	DC to 18 GHz Precision Fixed 20 dB Attenuator	CBT	N/A	CBT	N/A
Mini-Circuits	NLP-2950+	Low Pass Filter DC to 2700 MHz	CBT	N/A	CBT	N/A
Mini-Circuits	NLP-1200+	Low Pass Filter DC to 1000 MHz	CBT	N/A	CBT	N/A
Mini-Circuits	BW-N20W5	Power Attenuator	CBT	N/A	CBT	1226
Mitutoyo	CD-6"CSX	Digital Caliper	4/18/2018	Biennial	4/18/2020	13264165
Narda	4772-3	Attenuator (3dB)	CBT	N/A	CBT	9406
Narda	BW-S3W2	Attenuator (3dB)	CBT	N/A	CBT	120
Narda	4014C-6	4 - 8 GHz SMA 6 dB Directional Coupler	CBT	N/A	CBT	N/A
Pasternack	PE2208-6	Bidirectional Coupler	CBT	N/A	CBT	N/A
Pasternack	PE2209-10	Bidirectional Coupler	CBT	N/A	CBT	N/A
Pasternack	NC-100	Torque Wrench	5/23/2018	Biennial	5/23/2020	N/A
Pasternack	NC-100	Torque Wrench	11/7/2017	Biennial	11/7/2019	N/A
Rohde & Schwarz	CMW500	Radio Communication Tester	8/26/2019	Annual	8/26/2020	100976
Rohde & Schwarz	CMW500	Radio Communication Tester	6/26/2019	Annual	6/26/2020	112347
Rohde & Schwarz	CMU200	Base Station Simulator	6/3/2019	Annual	6/3/2020	109892
SPEAG	EX3DV4	SAR Probe	7/16/2019	Annual	7/16/2020	7410
SPEAG	DAE4	Dasy Data Acquisition Electronics	7/16/2019	Annual	7/16/2020	1322
		, , ,				
SPEAG	D1765V2	1765 MHz SAR Dipole	5/23/2018	Biennial	5/23/2020	1008
SPEAG	D2600V2	2600 MHz SAR Dipole	6/14/2019	Annual	6/14/2020	1064
SPEAG	D1900V2	1900 MHz SAR Dipole	2/21/2019	Biennial	2/21/2021	5d148
SPEAG	D2450V2	2450 MHz SAR Dipole	8/14/2019	Annual	8/14/2020	719
SPEAG	DAK-3.5	Dielectric Assessment Kit	5/7/2019	Annual	5/7/2020	1070
Rohde & Schwarz	NRP8S	3 Path Diode Power Sensor	6/1/2019	Annual	6/1/2020	108168
Mini Circuits	ZAPD-2-272-S+	Power Splitter	CBT	N/A	CBT	SF702001405

Notes:

CBT (Calibrated Before Testing). Prior to testing, the measurement paths containing a cable, amplifier, attenuator, coupler or filter were 1. connected to a calibrated source (i.e. a signal generator) to determine the losses of the measurement path. The power meter offset was then adjusted to compensate for the measurement system losses. This level offset is stored within the power meter before measurements are made. This calibration verification procedure applies to the system verification and output power measurements. The calibrated reading is then taken directly from the power meter after compensation of the losses for all final power measurements.

2. Each equipment item is used solely within its respective calibration period

FCC ID: A3LSMG986JPN	PCTEST <sup>®</sup> Proud to be part of <sup>®</sup> element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dama 44 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 41 of 45
© 2020 PCTEST				REV 1.0

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#### 12 **MEASUREMENT UNCERTAINTIES**

		-					1	1
а	с	d	e=	f	g	h =	i =	k
			f(d,k)			c x f/e	c x g/e	
	Tol.	Prob.		c <sub>i</sub>	ci	1gm	10gms	
Uncertainty Component	(± %)	Dist.	Div.	1gm	10 gms	ui	ui	vi
					_	(± %)	(± %)	
Measurement System								
Probe Calibration	6.55	N	1	1.0	1.0	6.6	6.6	x
Axial Isotropy	0.25	Ν	1	0.7	0.7	0.2	0.2	x
Hemishperical Isotropy	1.3	Ν	1	0.7	0.7	0.9	0.9	x
Boundary Effect	2.0	R	1.73	1.0	1.0	1.2	1.2	x
Linearity	0.3	Ν	1	1.0	1.0	0.3	0.3	x
System Detection Limits	0.25	R	1.73	1.0	1.0	0.1	0.1	8
Readout Electronics	0.3	Ν	1	1.0	1.0	0.3	0.3	8
Response Time	0.8	R	1.73	1.0	1.0	0.5	0.5	8
Integration Time	2.6	R	1.73	1.0	1.0	1.5	1.5	8
RF Ambient Conditions - Noise	3.0	R	1.73	1.0	1.0	1.7	1.7	8
RF Ambient Conditions - Reflections	3.0	R	1.73	1.0	1.0	1.7	1.7	8
Probe Positioner Mechanical Tolerance	0.4	R	1.73	1.0	1.0	0.2	0.2	8
Probe Positioning w/ respect to Phantom	6.7	R	1.73	1.0	1.0	3.9	3.9	8
Extrapolation, Interpolation & Integration algorithms for Max. SAR Evaluation	4.0	R	1.73	1.0	1.0	2.3	2.3	œ
Test Sample Related								
Test Sample Positioning	2.7	Ν	1	1.0	1.0	2.7	2.7	35
Device Holder Uncertainty	1.67	Ν	1	1.0	1.0	1.7	1.7	5
Output Power Variation - SAR drift measurement	5.0	R	1.73	1.0	1.0	2.9	2.9	x
SAR Scaling	0.0	R	1.73	1.0	1.0	0.0	0.0	x
Phantom & Tissue Parameters								
Phantom Uncertainty (Shape & Thickness tolerances)	7.6	R	1.73	1.0	1.0	4.4	4.4	8
Liquid Conductivity - measurement uncertainty	4.2	N	1	0.78	0.71	3.3	3.0	10
Liquid Permittivity - measurement uncertainty	4.1	N	1	0.23	0.26	1.0	1.1	10
Liquid Conductivity - Temperature Uncertainty	3.4	R	1.73	0.78	0.71	1.5	1.4	$\infty$
Liquid Permittivity - Temperature Unceritainty	0.6	R	1.73	0.23	0.26	0.1	0.1	x
Liquid Conductivity - deviation from target values	5.0	R	1.73	0.64	0.43	1.8	1.2	x
Liquid Permittivity - deviation from target values	5.0	R	1.73	0.60	0.49	1.7	1.4	x
Combined Standard Uncertainty (k=1)		RSS				11.5	11.3	60
Expanded Uncertainty		k=2				23.0	22.6	_
(95% CONFIDENCE LEVEL)		K-2				23.0	22.0	

FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dama 40 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 42 of 45
© 2020 PCTEST				REV 1.0 04/06/2020

#### 13 CONCLUSION

#### 13.1 Measurement Conclusion

The SAR evaluation indicates that the DUT complies with the RF radiation exposure limits of the FCC and Innovation, Science, and Economic Development Canada, with respect to all parameters subject to this test. These measurements were taken to simulate the RF effects of RF exposure under worst-case conditions. Precise laboratory measures were taken to assure repeatability of the tests. The results and statements relate only to the item(s) tested.

Please note that the absorption and distribution of electromagnetic energy in the body are very complex phenomena that depend on the mass, shape, and size of the body, the orientation of the body with respect to the field vectors, and the electrical properties of both the body and the environment. Other variables that may play a substantial role in possible biological effects are those that characterize the environment (e.g. ambient temperature, air velocity, relative humidity, and body insulation) and those that characterize the individual (e.g. age, gender, activity level, debilitation, or disease). Because various factors may interact with one another to vary the specific biological outcome of an exposure to electromagnetic fields, any protection guide should consider maximal amplification of biological effects as a result of field-body interactions, environmental conditions, and physiological variables. [3]

FCC ID: A3LSMG986JPN	PCTEST* Froud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 42 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 43 of 45
© 2020 PCTEST	· · · · ·			REV 1.0

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FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dogo 44 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Page 44 of 45
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FCC ID: A3LSMG986JPN	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Page 45 of 45
1M2001240012-20-R1.A3L	03/13/2020 - 04/06/2020	Portable Handset		Fage 45 01 45
O 2020 POTEST				DEV/10

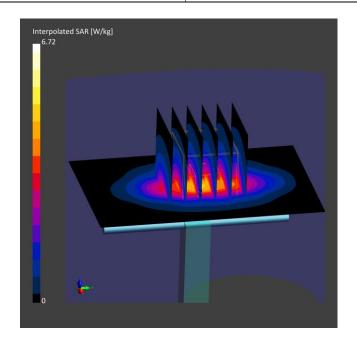
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## APPENDIX A: SYSTEM VERIFICATIONS

Date: 04-01-2020

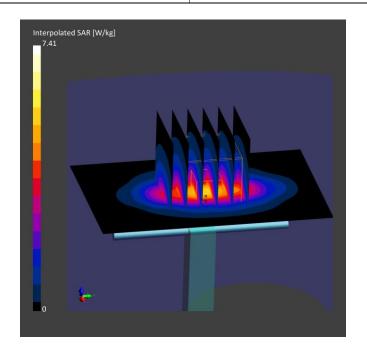
1750 MHz Body Verification

Frequency [MHz]		TSL		TSL Conductivity [S/m]	TSL Permittivity	Ambient Temperature [°C]	Tissue Temperature [°C]	
1750.0		1750 Body		1.46	51.2	22.0	21.1	
Hardware Setup						1		
Phantom	Dipole	Power [dBm]	Test Distance [mm]	Probe, Calibration	n Date	DAE, Calibratio	n Date	
Twin-SAM V5.0 (30deg probe tilt)	D1765V2 - SN1008	20.0	10	EX3DV4 - SN741	0, 2019-07-16	DAE4 Sn1322, 2	2019-07-11	
Scans Setup				1				
			Area Scan				Zoom Scan	
Grid Extents [mm]			60.0 × 90.0			30.0 x 30.0 x 30.0		
Grid Steps [mm]			15.0 x 15.0			6.0 x 6.0 x 5.0		
Sensor Surface [mm	]		1.4		١			
Graded Grid			No					
Grading Ratio			n/a		n/a			
Measurement Re	sults							
							Zoom Scan	
psSAR1g [W/Kg]				3.89				
Dev. 1g [%]				4.01			4.01%	



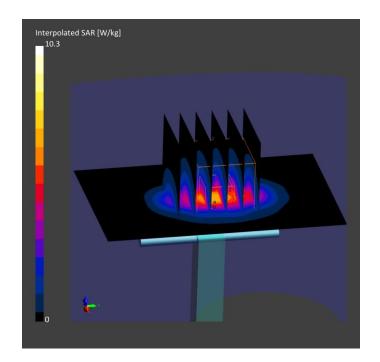
Date: 04-01-2020 1900 MHz Body Verification

Frequency [MHz]		TSL		TSL Conductivity [S/m]	TSL Permittivity	Ambient Temperature [°C]	Tissue Temperature [°C]
1900.0		1900 Body		1.56	51.0	22.0	21.1
Hardware Setup							
Phantom	Dipole	Power [dBm]	Test Distance [mm]	Probe, Calibratio	n Date	DAE, Calibration	n Date
Twin-SAM V5.0 (30deg probe tilt)	D1900V2 - SN5d148	20.0	10	EX3DV4 - SN741	0, 2019-07-16	DAE4 Sn1322, 2	2019-07-11
Scans Setup							
			Area Scan				Zoom Scan
Grid Extents [mm]			60.0 × 90.0		30.0 × 30.0 × 30.0		
Grid Steps [mm]			15.0 x 15.0		6.0 × 6.0 × 5		
Sensor Surface [mm	]		1.4	1.4			1.4
Graded Grid No		No	N			No	
Grading Ratio		n/a		n/			n/a
Measurement Re	sults						
							Zoom Scan
psSAR1g [W/Kg]	psSAR1g [W/Kg]		4.20				
Dev. 1g [%]				8.9			8.95%



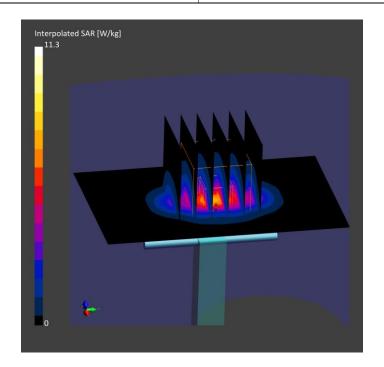
Date: 04-01-2020 2450 MHz Body Verification

Frequency [MHz]		TSL		TSL Conductivity [S/m]	TSL Permittivity	Ambient Temperature [°C]	Tissue Temperature [°C]	
2450.0		2450 Body		2.02	50.3	22.0	21.1	
Hardware Setup								
Phantom	Dipole	Power [dBm]	Test Distance [mm]	Probe, Calibratio	n Date	DAE, Calibration	n Date	
Twin-SAM V5.0 (30deg probe tilt)	D2450V2 - SN719	20.0	10	EX3DV4 - SN741	0, 2019-07-16	DAE4 Sn1322, 2	2019-07-11	
Scans Setup				1				
			Area Scan				Zoom Scan	
Grid Extents [mm]			60.0 × 90.0		30.0 × 30.0 × 30.0			
Grid Steps [mm]			12.0 x 12.0	5.0 x 5.0 x 5.0				
Sensor Surface [mm	]		1.4					
Graded Grid			No					
Grading Ratio			n/a		n/			
Measurement Re	sults							
							Zoom Scan	
psSAR1g [W/Kg]				5.2				
Dev. 1g [%]				3.94			3.94%	



Date: 04-01-2020 2600 MHz Body Verification

Frequency [MHz]		TSL		TSL Conductivity [S/m]	TSL Permittivity	Ambient Temperature [°C]	Tissue Temperature [°C]
2600.0		2450 Body		2.17	50.0	22.0	21.1
Hardware Setup							<u> </u>
Phantom	Dipole	Power [dBm]	Test Distance [mm]	Probe, Calibratio	n Date	DAE, Calibratio	n Date
Twin-SAM V5.0 (30deg probe tilt)	D2600V2 - SN1064	20.0	10	EX3DV4 - SN741	0, 2019-07-16	DAE4 Sn1322, 3	2019-07-11
Scans Setup							
			Area Scan				Zoom Scan
Grid Extents [mm]			60.0 x 90.0		30.0 × 30.0 × 30.0		
Grid Steps [mm]			12.0 x 12.0		5.0 x 5.0 x 5		5.0 x 5.0 x 5.0
Sensor Surface [mm	]		1.4	1.4			
Graded Grid			No				
Grading Ratio			n/a				n/a
Measurement Re	sults						
							Zoom Scan
psSAR1g [W/Kg]		5.5					
Dev. 1g [%]				0.36			0.36%



### APPENDIX B: SAR TISSUE SPECIFICATIONS

Measurement Procedure for Tissue verification:

- 1) The network analyzer and probe system was configured and calibrated.
- The probe was immersed in the tissue. The tissue was placed in a nonmetallic container. Trapped air bubbles beneath the flange were minimized by placing the probe at a slight angle.
- 3) The complex admittance with respect to the probe aperture was measured
- The complex relative permittivity ε can be calculated from the below equation (Pournaropoulos and Misra):

$$Y = \frac{j2\omega\varepsilon_{r}\varepsilon_{0}}{\left[\ln(b/a)\right]^{2}} \int_{a}^{b} \int_{0}^{a} \int_{0}^{\pi} \cos\phi' \frac{\exp\left[-j\omega r(\mu_{0}\varepsilon_{r}'\varepsilon_{0})^{1/2}\right]}{r} d\phi' d\rho' d\rho$$

where Y is the admittance of the probe in contact with the sample, the primed and unprimed coordinates refer to source and observation points, respectively,  $r^2 = \rho^2 + {\rho'}^2 - 2\rho\rho' \cos\phi'$ ,  $\omega$  is the angular frequency, and  $j = \sqrt{-1}$ .

### 3 Composition / Information on ingredients

3.2 Mixtures Description: Aqueous solution with Declarable, or hazardous compon		
CAS: 107-21-1	Ethanediol	>1.0-4.9%
EINECS: 203-473-3	STOT RE 2, H373;	
Reg.nr.: 01-2119456816-28-0000	Acute Tox. 4, H302	
CAS: 68608-26-4	Sodium petroleum sulfonate	< 2.9%
EINECS: 271-781-5	Eye Irrit. 2, H319	
Reg.nr.: 01-2119527859-22-0000		
CAS: 107-41-5	Hexylene Glycol / 2-Methyl-pentane-2,4-diol	< 2.9%
EINECS: 203-489-0	Skin Irrit. 2, H315; Eye Irrit. 2, H319	
Reg.nr.: 01-2119539582-35-0000		
CAS: 68920-66-1	Alkoxylated alcohol, > C <sub>16</sub>	< 2.0%
NLP: 500-236-9	Aquatic Chronic 2, H411;	
Reg.nr.: 01-2119489407-26-0000	Skin Irrit. 2, H315; Eye Irrit. 2, H319	
Additional information:		

For the wording of the listed risk phrases refer to section 16.

Not mentioned CAS-, EINECS- or registration numbers are to be regarded as Proprietary/Confidential. The specific chemical identity and/or exact percentage concentration of proprietary components is withheld as a trade secret.

d as a trade secret.

### Figure B - 1

Note: Liquid recipes are proprietary SPEAG. Since the composition is approximate to the actual liquids utilized, the manufacturer tissue-equivalent liquid data sheets are provided below.

FCC ID: A3LSMG986JPN	PART 2 RF EXPOSURE EVALUATION REPORT	<b>Approved by:</b> Quality Manager
Test Dates:	DUT Type:	APPENDIX B:
03/13/2020 - 04/06/2020	Portable Handset	Page 1 of 2



Zeughausstrasse 43, 8004 Zurich, Switzerland Phone +41 44 245 9700, Fax +41 44 245 9779 info@speag.com, http://www.speag.com

### Measurement Certificate / Material Test

Item Name	Body Tissue Simulating Liquid (MBBL600-6000V6)
Product No.	SL AAM U16 BC (Batch: 181029-1)
Manufacturer	SPEAG

#### Measurement Method

TSL dielectric parameters measured using calibrated DAK probe.

Target Parameters Target parameters as defined in the KDB 865664 compliance standard.

Ambient Condition	22°C ; 30% humidity	
TSL Temperature	22°C	
Test Date	30-Oct-18	
Operator	CL	
Additional Inform	ation	
TSL Density		
TSL Heat-capacity		

3500 4500 5500

> 4500 5500

3.31

3.55 -0.5 -8.8

5.36 5.42

5.77

5.88 -2.5 1.8

5.65 -2.2

6.00 -2.6

-0.4 -8.8

0.8

1.3

5.30 -1.8 -0.6 -1.9 -2.0 -0.4 -0.2

-2.3

#### Results

Т

	Measu	ured		Targe	et	Diff.to Tar	get [%]	
f (MHz)	e'	e"	sigma	eps	sigma	∆-eps	∆-sigma	15.0
800	55.1	21.3	0.95	55.3	0.97	-0.4	-2.1	10.0
825	55.1	20.8	0.96	55.2	0.98	-0.3	-2.0	and the second second
835	55.1	20.6	0.96	55.1	0.99	0.0	-2.5	* 5.0
850	55.1	20.4	0.96	55.2	0.99	-0.1	-3.0	0.0 trivit
900	55.0	19.7	0.98	55.0	1.05	0.0	-6.7	Ť.
1400	54.2	15.6	1.22	54.1	1.28	0.2	-4.7	دَّ -5.0 >
1450	54.1	15.4	1.24	54.0	1.30	0.2	-4.6	% (Avitation of the second of
1500	54.1	15.3	1.27	53.9	1.33	0.3	-4.5	
1550	54.0	15.1	1.30	53.9	1.36	0.2	-4.4	-15.0
1600	53.9	15.0	1.33	53.8	1.39	0.2	-4.3	Frequency M
1625	53.9	14.9	1.35	53.8	1.41	0.3	-4.3	
1640	53.9	14.9	1.36	53.7	1.42	0.3	-4.2	15.0
1650	53.8	14.9	1.36	53.7	1.43	0.2	-4.9	15.0
1700	53.8	14.8	1.40	53.6	1.46	0.4	-4.1	10.0
1750	53.7	14.7	1.43	53.4	1.49	0.5	-4.0	× 5.0
1800	53.7	14.6	1.46	53.3	1.52	0.8	-3.9	5.0 0.0 0.0 0.0 0.0 0.0 0.0 0.0 0.0
1810	53.7	14.6	1.47	53.3	1.52	0.8	-3.3	B 0.0 - · · · · · · · · · · · · · · · · · ·
1825	53.7	14.6	1.48	53.3	1.52	0.8	-2.6	δ5.0 Λ ~ \
1850	53.6	14.5	1.50	53.3	1.52	0.6	-1.3	
1900	53.5	14.5	1.53	53.3	1.52	0.4	0.7	-10.0
1950	53.5	14.5	1.57	53.3	1.52	0.4	3.3	-15.0
2000	53.4	14.4	1.60	53.3	1.52	0.2	5.3	500 1500 2500 350
2050	53.4	14.4	1.64	53.2	1.57	0.3	4.5	Frequency MH
2100	53.3	14.4	1.68	53.2	1.62	0.2	3.7	
2150	53.3	14.4	1.72	53.1	1.66	0.4	3.6	
2200	53.2	14.4	1.76	53.0	1.71	0.3	2.9	3500 51.1 15.5 3.02 51.3
2250	53.1	14.4	1.81	53.0	1.76	0.2	2.8	3700 50.8 15.7 3.24 51.1
2300	53.1	14.4	1.85	52.9	1.81	0.4	2.2	5200 48.1 18.2 5.27 49.0
2350	53.0	14.5	1.89	52.8	1.85	0.3	2.2	5250 48.0 18.3 5.34 49.0
2400	52.9	14.5	1.94	52.8	1.90	0.2	2.1	5300 47.9 18.4 5.41 48.9
2450	52.9	14.5	1.98	52.7	1.95	0.4	1.5	5500 47.5 18.6 5.70 48.6
2500	52.8	14.6	2.03	52.6	2.02	0.3	0.5	5600 47.3 18.8 5.84 48.5
2550	52.7	14.6	2.07	52.6	2.09	0.2	-1.0	5700 47.1 18.9 5.99 48.3
2600	52.6	14.7	2.12	52.5	2.16	0.2	-1.9	5800 47.0 19.0 6.14 48.2

TSL Dielectric Parameters

# Figure B-2 600 – 5800 MHz Body Tissue Equivalent Matter

FCC ID: A3LSMG986JPN	PART 2 RF EXPOSURE EVALUATION REPORT	Approved by: Quality Manager
Test Dates:	DUT Type:	APPENDIX B:
03/13/2020 - 04/06/2020	Portable Handset	Page 2 of 2

### APPENDIX C: SAR SYSTEM VALIDATION

Per FCC KDB Publication 865664 D02v01r02, SAR system validation status should be documented to confirm measurement accuracy. The SAR systems (including SAR probes, system components and software versions) used for this device were validated against its performance specifications prior to the SAR measurements. Reference dipoles were used with the required tissue- equivalent media for system validation, according to the procedures outlined in FCC KDB Publication 865664 D01v01r04 and IEEE 1528-2013. Since SAR probe calibrations are frequency dependent, each probe calibration point was validated at a frequency within the valid frequency range of the probe calibration point, using the system that normally operates with the probe for routine SAR measurements and according to the required tissue-equivalent media.

A tabulated summary of the system validation status including the validation date(s), measurement frequencies, SAR probes and tissue dielectric parameters has been included.

SAR	FREQ.		PROBE			COND.	PERM.	C	W VALIDATIO	N	M	OD. VALIDATIO	N
SYSTEM	[MHz]	DATE	SN	PROBE C	AL. POINT	(a)	(cr)	SENSITIVITY	PROBE	PROBE	MOD.	DUTY	PAR
#	[IVIH2]		SIN			(σ)	(ɛr)	SENSITIVIT	LINEARITY	ISOTROPY	TYPE	FACTOR	FAR
L	1750	8/16/2019	7410	1750	Body	1.467	53.429	PASS	PASS	PASS	N/A	N/A	N/A
L	1900	8/16/2019	7410	1900	Body	1.157	53.200	PASS	PASS	PASS	GMSK	PASS	N/A
L	2450	8/15/2019	7410	2450	Body	2.018	52.505	PASS	PASS	PASS	OFDM/TDD	PASS	PASS
L	2600	8/16/2019	7410	2600	Body	2.161	52.297	PASS	PASS	PASS	TDD	PASS	N/A

Table C-1 SAR System Validation Summary – 1g

NOTE: While the probes have been calibrated for both CW and modulated signals, all measurements were performed using communication systems calibrated for CW signals only. Modulations in the table above represent test configurations for which the measurement system has been validated per FCC KDB Publication 865664 D01v01r04 for scenarios when CW probe calibrations are used with other signal types. SAR systems were validated for modulated signals with a periodic duty cycle, such as GMSK, or with a high peak to average ratio (>5 dB), such as OFDM according to FCC KDB Publication 865664 D01v01r04.

FCC ID: A3LSMG986JPN		SAMSUNG	Approved by: Quality Manager
Test Dates:	DUT Type:		APPENDIX C: Page 1 of 1
03/13/2020 - 04/06/2020	Portable Handset		i ago i oi i

### **APPENDIX E: TEST SEQUENCES**

- 1. Test sequence is generated based on below parameters of the DUT:
  - a. Measured maximum power ( $P_{max}$ )
  - b. Measured Tx\_power\_at\_SAR\_design\_target (P<sub>limit</sub>)
  - c. Reserve\_power\_margin (dB)
    - P<sub>reserve</sub> (dBm) = measured P<sub>limit</sub> (dBm) Reserve\_power\_margin (dB)
  - d. SAR\_time\_window (100s for FCC)
- 2. Test Sequence 1 Waveform:

Based on the parameters above, the Test Sequence 1 is generated with one transition between high and low Tx powers. Here, high power =  $P_{max}$ ; low power =  $P_{max}/2$ , and the transition occurs after 80 seconds at high power  $P_{max}$ . As long as the power enforcement is taking into effective during one 100s/60s time window, the validation test with this defined test sequence 1 is valid, otherwise, select other radio configuration (band/DSI within the same technology group) having lower  $P_{limit}$  for this test. The Test sequence 1 waveform is shown below:

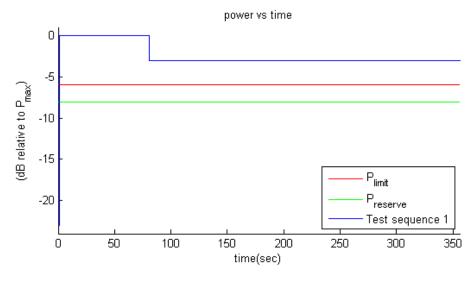


Figure E-1 Test sequence 1 waveform

	FCC ID:	A3LSMG986JPN		Approved by: Quality Manager
	Test Dates:		DUT Type:	APPENDIX E:
	03/13/20	20 - 04/06/2020	Portable Handset	Page 1 of 3
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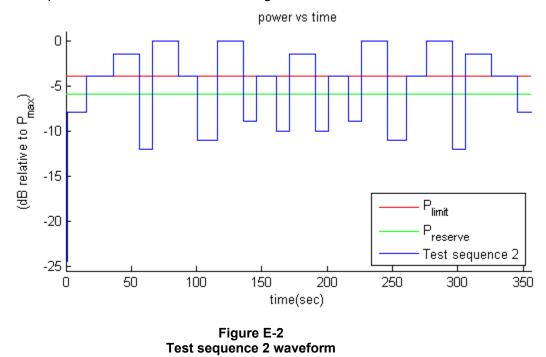
### 3. Test Sequence 2 Waveform:

Based on the parameters described above, the Test Sequence 2 is generated as described in Table 10-1, which contains two 170 second-long sequences (yellow and green highlighted rows) that are mirrored around the center row of 20s, resulting in a total duration of 360 seconds:

Time duration (seconds)	dB relative to <i>P</i> <sub>limit</sub> or <i>P</i> <sub>reserve</sub>
<mark>15</mark>	P <sub>reserve</sub> – 2
<mark>20</mark>	P <sub>limit</sub>
20	( <i>P<sub>limit</sub> + P<sub>max</sub>)</i> /2 averaged in mW and rounded to nearest 0.1 dB step
<mark>10</mark>	P <sub>reserve</sub> – 6
<mark>20</mark>	P <sub>max</sub>
<mark>15</mark>	P <sub>limit</sub>
<mark>15</mark>	P <sub>reserve</sub> – 5
<mark>20</mark>	P <sub>max</sub>
<mark>10</mark>	P <sub>reserve</sub> – 3
<mark>15</mark>	P <sub>limit</sub>
<mark>10</mark>	P <sub>reserve</sub> – 4
20	$(P_{limit} + P_{max})/2$ averaged in mW and rounded to nearest 0.1 dB step
10	P <sub>reserve</sub> – 4
<mark>15</mark>	P <sub>limit</sub>
<mark>10</mark>	P <sub>reserve</sub> – 3
<mark>20</mark>	P <sub>max</sub>
<mark>15</mark>	P <sub>reserve</sub> – 5
<mark>15</mark>	P <sub>limit</sub>
20	P <sub>max</sub>
<mark>10</mark>	P <sub>reserve</sub> – 6
20	( <i>P<sub>limit</sub></i> + <i>P<sub>max</sub></i> )/2 averaged in mW and rounded to nearest 0.1 dB step
20	P <sub>limit</sub>
15	P <sub>reserve</sub> – 2

Table E-1 Test Sequence 2

	FCC ID:	A3LSMG986JPN	PCTEST Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	<b>Approved by:</b> Quality Manager
	Test Dat	es:	DUT Type:			APPENDIX E:
	03/13/202	20 – 04/06/2020	Portable Handset			Page 2 of 3
© 202	0 PCTEST					REV 1.0 04/06/2020



The Test Sequence 2 waveform is shown in Figure E-2.

